R&S®ESSENTIALS MXO 4 Series OSCILLOSCOPE

Next generation oscilloscope for accelerated insight



Product Brochure Version 13.00

Oscilloscope innovation. Measurement confidence. www.rohde-schwarz.com/product/MXO4

ROHDE&SCHWARZ

Make ideas real



NEXT GENERATION TECHNOLOGY MXO 4 Series OSCILLOSCOPE

The MXO 4 series is the first of a new generation of oscilloscopes that excels in both performance and value. The instruments deliver a once-in-a-decade engineering breakthrough for accelerated insight.



A touch above other oscilloscopes in its class, the MXO 4 series oscilloscope sports an impressive 13.3" Full HD capacitive touchscreen and an intuitive user interface with a learning curve of less than 15 minutes.

WHY ENGINEERS CONTINUE TO UPGRADE TO ROHDE & SCHWARZ OSCILLOSCOPES

- A trusted, global high-quality company with a long-standing commitment to customers and continuous technological innovation
- The newest oscilloscope portfolio from 60 MHz to 16 GHz
- In-house ASICs developed for the world's most responsive oscilloscopes
- ► Frontend technology development for pristine signal integrity
- 16-bit and 18-bit architectures with HD mode for the highest resolution
- ▶ Digital triggering for the world's most sensitive event isolation
- Superior user interface and front panel that streamlines workflows

WHY USE THE MXO 4

- World's first oscilloscope with update rate exceeding 4.5 million waveforms per second
- ► Industry leading 12-bit ADC at all sample rates
- ► Industry best 18-bit architecture
- Fastest and most accurate spectrum analysis in its class
- ► Industry's deepest standard memory of 400 Mpoints per channel
- ► Industry's fastest trigger rearm time of 21 ns
- First in class to incorporate new digital triggering technology
- ► Industry's most sensitive trigger of 0.0001 div
- ▶ Best in class trigger jitter of < 1 ps
- First oscilloscope with dual-path protocol analysis
- ► First in class with R&S[®]SmartGrid user interface

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PROBES AND ACCESSORIES

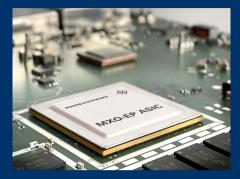
Extensive probe portfolio ► page 28

And there is so much more ... ▶ page 31

- 200 MHz to 1.5 GHz bandwidth
- Up to 5 Gsample/s sample rate
- 400 Mpoints per channel standard memory
- 12-bit ADC at all sample rates
- 18-bit architecture with HD mode
- Precise digital trigger

CUTTING-EDGE TECHNOLOGY BLOCKS THAT HELP GIVE YOU ACCELERATED INSIGHT

The MXO 4 series oscilloscopes utilize advanced technologies to achieve fast and accurate results. Custom technology and innovative features in our oscilloscopes quickly boost your understanding of circuit behaviors.



MXO-EP processing ASIC

See more of your signals, faster

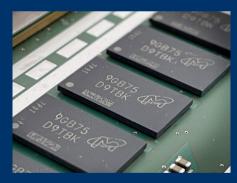
At the heart of each MXO 4 series oscilloscope is a Rohde&Schwarz developed application-specific integrated circuit (ASIC): MXO-EP (extreme performance). MXO-EP processes 200 Gbit/s to deliver the world's fastest update rate of up to > 4.5 million acquisitions/s. See and capture more of your signals, faster. Find rare signal anomalies quickly. Experience the most responsive oscilloscope in the industry.



12-bit ADC, 18-bit vertical architecture

Measure your signals accurately.

Measurement accuracy is highly dependent on the components in the signal path, e.g. amplifiers, samplers and A/D converters. The workhorse of the MXO 4 series is an extremely low-noise signal path including a 12-bit ADC. High-definition (HD) mode increases vertical resolution to industry best 18-bit architecture. The ultra-low noise and high precision provides up to 10 effective number of bits (ENOB). Get accurate measurements all the time.



Responsive deep memory Capture more of your signals

MXO 4 series oscilloscopes come equipped with the industry's deepest standard acquisition memory of 400 Mpoints per channel. Capture up to 80 ms of power up or power down sequences with the highest time resolution of 200 ps. The memory controller in the MXO-EP ASIC ensures the oscilloscope stays responsive with deep memory.



Advanced digital triggering system Easily isolate subtle signal variations.

The MXO-EP ASIC incorporates advanced digital triggering that evaluates the ADC samples in the acquisition path in real time. Trigger on small events of less than 0.0001 vertical division that no other oscilloscope can isolate. Choose your own trigger hysteresis. Apply digital filters to suppress noise to get the most precise triggering available. The implemented zone trigger retains ultra fast acquisition speed and versatility and can work across channel waveforms, spectra and math signals.

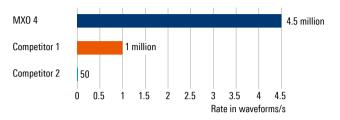
FIND SIGNAL ANOMALIES OUICKLY WITH UNPARALLELED UPDATE RATES

- ▶ World's fastest acquisition rate of up to > 4.5 million waveforms/s reveals infrequent anomalies instantly
- ▶ Up to 90 % real-time signal capture and display ensures instant display of all signal details
- ► Signal processing based on MXO-EP ASIC ensures responsive deep memory

World's fastest update rate

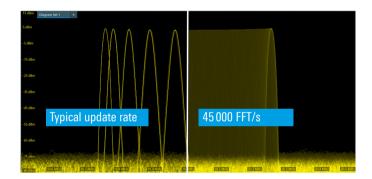
The MXO 4 oscilloscope processing path contains a dedicated ASIC: the MXO-EP (extreme performance). Thanks to optimized signal processing, the MXO 4 oscilloscope reaches an exceptional update rate. Its unique architecture allows the MXO 4 to acquire, process and display up to > 4.5 million waveforms/s.

Real-time acquisition rate



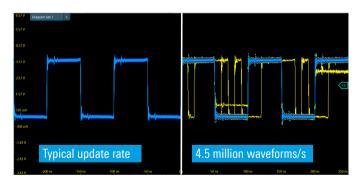
Available with active automatic measurements, FFTs or cursor measurements

The MXO 4 oscilloscope offers a high update rate even when FFTs, automatic measurements or cursor measurements are active. Also when performing analysis with deep memory acquisitions, the MXO-EP based signal processing path ensures smooth workflows.



Quickly and reliably detect sporadic signal faults

The statistical confidence in results grows with the number of waveforms acquired. A high update rate increases the likelihood of detecting and displaying signal faults and including them in the analysis. Its high update rate enables the MXO 4 to generate trustworthy statistical results based on a high number of waveforms acquired in a short time. This is crucial for quickly understanding electronic circuits.

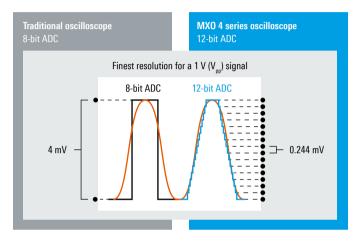


SEE YOUR SIGNALS ACCURATELY LOWEST MEASUREMENT NOISE AND HIGHEST VERTICAL RESOLUTION

- ▶ 12-bit ADC for high vertical resolution at all sample rates across the full bandwidth
- ▶ 18-bit architecture with HD mode
- Low noise at 50 Ω input impedance (1 mV/div setting)
 - 104 μV (at 1 GHz, 12-bit standard mode)
 - 56 μ V (at 500 MHz, 14-bit HD mode)
- ► ENOB performance of > 10 bit
- \blacktriangleright Industry's highest available offset range of ±5 V at 500 $\mu\text{V/div}$

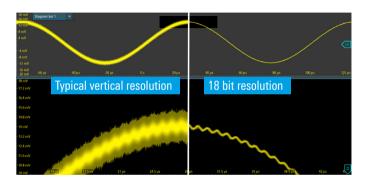
12-bit ADC even at the fastest sample rates

All MXO 4 series oscilloscopes incorporate a 12-bit ADC. 12 bit vertical resolution delivers 4096 quantization levels for precise vertical sampling. This is a 16-fold improvement over 8-bit ADCs. The ADC stays in 12-bit mode all the time, even at the fastest sample rates.



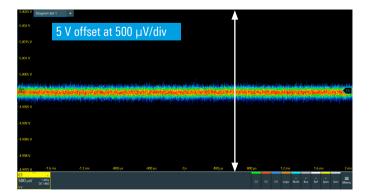
18-bit architecture with HD mode

Offering a user tradeoff between bandwidth and bits of resolution, HD mode, implemented in hardware for fast speed, achieves up to 18 bit vertical resolution. This allows you to see sharper waveforms with more signal details that would otherwise be masked by noise. In addition to superior vertical resolution, the MXO 4 series oscilloscope is engineered with the lowest-in-industry system measurement noise of just 22 μ V AC (RMS) at 1 mV/div.



Vertical sensitivity to 500 μ V/div with ±5 V offset range

The MXO 4 series oscilloscope offers an outstanding sensitivity down to 500 μ V/div without any unexpected reduction in bandwidth. With an offset of ±5 V at higher sensitivity vertical scale, you can easily place the signal at the center of the screen. A higher offset enables use of more sensitive vertical resolution, meaning a higher number of ADC bits and lower noise.



CAPTURE MORE TIME DEEPEST STANDARD MEMORY

- ▶ Industry's deepest memory of 400 Mpoints per channel (optionally 800 Mpoints interleaved)
- ► Standard segmented memory (10 000 segments, optionally 1 000 000 segments)
- Standard history mode (10 000 acquisitions, optionally 1 000 000 acquisitions)

Deep memory as an insurance policy

After bandwidth and sample rate, memory depth is the most important attribute that determines an oscilloscope's ability to handle a large range of troubleshooting tasks. More acquisition memory gives oscilloscopes the ability to capture more time. More memory enables oscilloscopes to retain the maximum sample rate and bandwidth even with slower timebase settings.

With 400 Mpoints acquisition memory standard on all four channels simultaneously, the MXO 4 series oscilloscope offers up to 100 times the standard memory compared to the primary competitor.

Maintain fast sample rates with slow timebase settings

Ever adjusted your oscilloscope timebase to capture longer periods of time, pressed stop, then zoomed in to find signal details that do not look right? If so, you have experienced the aliasing problem that oscilloscopes with shallow memory have. The deep memory of the MXO 4 enables longer time captures at full sample rate.

Standard segmented memory

Use segmented memory to capture signals separated by inactivity. Examples include laser pulses, serial bus activities and RF pulses. The segmented memory of the MXO 4 series oscilloscope enables signal capture over a long observation period of up to 1000000 segments.

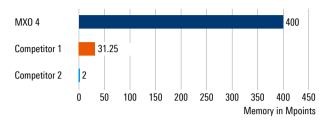
Standard history capability

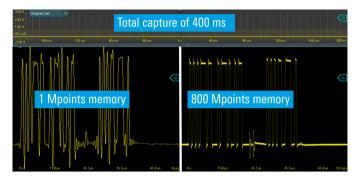
Press stop and use history mode to see previously captured acquisitions. History mode is an always-on capability. All measurement and analysis tools are available in history mode, including the serial bus decoding and automatic measurements.

Need even more memory?

During tests that involve looking at power up/power down behavior or decoding bus events over a longer period of time, there is always the wish to record longer time intervals. The memory extension option turns on 800 Mpoints (2 channels interleaved), up to 1000000 segments and up to 1000000 acquisitions.

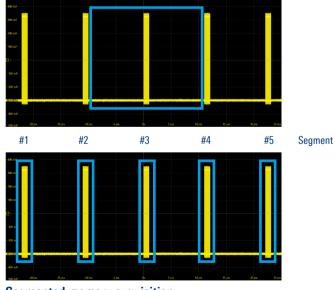
Standard memory per channel





Traditional single-shot acquisition

Total acquisition time = memory depth/sample rate



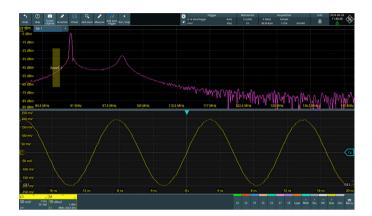
Segmented memory acquisition Acquisition time per segment = memory depth/# of segments

FASTEST ZONE TRIGGER VISUALIZE TRIGGER EVENT GRAPHICALLY

- ► Fastest zone trigger: 600 000 waveforms/s
- ► Draw a total of 32 zone areas: 4 zones with 8 zone areas each
- > Zone trigger across analog, spectrum and math sources
- ► Combine zone trigger with history and segmentation mode
- ► Compatible with FreeRun triggering

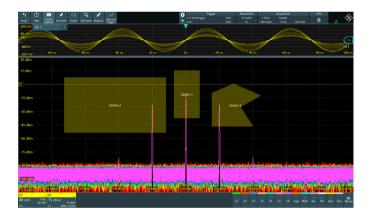
Easy trigger condition setup visually as standard feature

Designs are becoming more complex and predefined trigger conditions may no longer effectively capture needed events. The zone trigger on MXO series oscilloscopes can easily be drawn on signal diagrams to specify whether traces have to pass through defined areas to qualify. Simply activate the function on the toolbar and draw the area on an analog waveform, spectrum or even math to define complex trigger conditions.



Spectrum zone trigger

Rohde & Schwarz is the first in the industry to offer zone trigger capability for spectrum analysis. Starting with the R&S®RTO series, the MXO series has an even higher update rate for detecting spurious spectrum events. The responsive spectrum makes it ideal for EMI debugging. The fast zone trigger on the MXO series goes a step further and offers trigger capability across time, spectrum and even math waveforms.



32 zone trigger areas across analog sources, spectrum and math

Graphically define 32 zone areas (4 zones with up to 8 areas each) on the screen. You can use the MXO series zone triggering for analog signals, math functions, spectra and zoom windows. Combine zone trigger with the oscillo-scope FreeRun trigger mode to capture signals as quickly as possible without looking for a hardware trigger event.

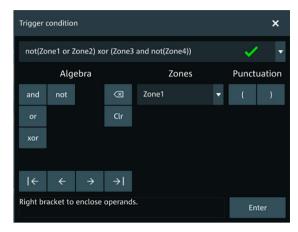
Zone trigg	jer					×
Setup	Zone1	Zone2	Zone3	•		Ô
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	1.4	Must not	-		AND	
		Must not	-		AND	
	1.6	Must not	-		AND	
	1.7	Must not	-		AND	
	1.8	Must	-		AND	
		A (C)	-			
		Area	Î			

Hardware accelerated zone trigger

Zone triggering complements traditional oscilloscope triggering to quickly and graphically isolate events. The MXO series zone trigger is implemented in the ASIC, the only hardware-accelerated solution and the fastest on the market with an update rate of 600 000 waveforms/s and less than 1.45 µs blind time between trigger events. The solution is up to 10 000x faster than competing zone triggering products. A more complex trigger setup with fast waveform acquisition is possible and increases the probability of isolating rare events without affecting responsiveness.

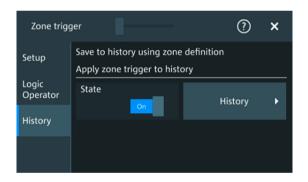
Complex HD trigger with zone logics

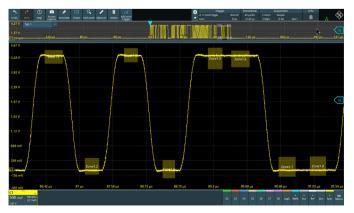
The MXO digital trigger can use the HD enhanced samples together with the zone trigger. Zones defined can also work across different sources. Logical definitions can enhance detection of required events.



Store zone trigger events in history

Apply zone triggering capability to history and segmentation mode and store only waveforms that match the zone trigger criteria in the oscilloscope memory. Very long time captures are possible when combined with the MXO series deep memory.





Use zone trigger on protocols to trigger on a specific packet sequence



Power rail measurements with zone trigger to isolate power consumption events during RF transmissions

ISOLATE EVENTS WITH MORE PRECISION HIGH-PRECISION DIGITAL TRIGGER

- ▶ Industry's most sensitive trigger: 0.0001 vertical division
- Best in class trigger jitter of just 1 ps
- World's fastest trigger rearm time of < 21 ns</p>
- Adjustable digital trigger filters
- User definable hysteresis

Modern digital trigger

The MXO-EP ASIC incorporates the Rohde&Schwarz patented digital trigger system. With digital triggering, signal measurement and triggering take place in a common path, whereas with older analog trigger architectures, incoming signals are split and fed to a measurement and a trigger path. Digital triggers offer numerous advantages.

Adjustable digital trigger filters

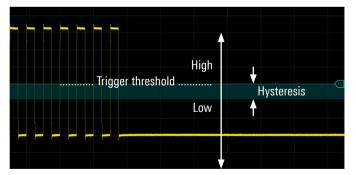
Use the up to 18-bit HD mode for triggering to reduce measurement system noise. The digital trigger architecture makes it possible to adapt the cutoff frequency of the digital lowpass filter to the signal to be measured. Conventional oscilloscopes limit triggering on filtered waveforms, on the MXO the same filter settings can be used for both the trigger signal and the measurement signal. As a result, noise on the trigger signal can be suppressed, for instance while simultaneously capturing and displaying the filtered or unfiltered measurement signal.

World's most sensitive trigger

The MXO 4 series digital trigger is up to 10000 times more sensitive than competing trigger systems. High trigger sensitivity enables users to isolate difficult-to-find small physical layer anomalies in the presence of large signals, accelerating debugging and troubleshooting.

User definable hysteresis

Use automated trigger hysteresis settings or manually enter your values. Unlike using oscilloscopes with analog triggers, MXO 4 series users have full access to control all trigger hysteresis settings. This provides additional flexibility for determining where to trigger, including how much trigger noise suppression is desired.





SPECTRUM ANALYSIS SUPERIOR RF MEASUREMENT CAPABILITY

- Pristine RF spectrum
- Dedicated RF controls
- ► RF/time domain views with independent controls
- Gated spectrum for easy correlation between frequency and time

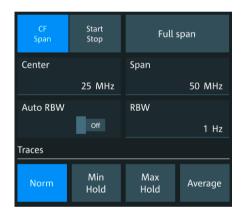
RF insights into your measurements

The MXO 4 series oscilloscope is engineered with spectrum analysis in mind to bring forward fast and powerful analysis capabilities. It boasts an industry leading spectrum acquisition rate of 45 000 FFT/s. This allows capture of spurious spectrum events, especially when doing EMI debugging. The pristine RF characteristics of the instrument deliver great spectrum performance together with a synchronized time domain view.

RF characteristics	
Simultaneous spectrum	up to 4 possible
Spectrum update rate	> 45 000 FFT/s
Sensitivity/noise power density	–160 dBm (1 Hz)
Noise figure	14 dB
Dynamic range	106 dB
Spurious-free dynamic range (SFDR)	65 dBc
Second harmonic distortion	-60 dBc
Third harmonic distortion	–59 dBc

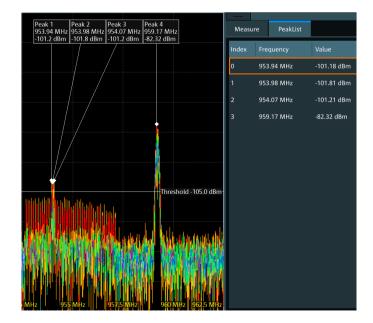
Frequency analysis setup made easy

You can configure spectrum analysis measurements on the MXO 4 by simply entering typical parameters: center frequency, span and resolution bandwidth (RBW). The spectrum settings are independent of the time domain settings but the time and frequency domains are time-correlated.



Automatic peak list and max./min. hold measurements

Rohde & Schwarz understands the need for additional tools in spectrum measurements. This is why the MXO 4 includes advanced spectrum analysis functions like max. and min. hold as well as peak list indication as part of the standard features. The values in the peak list are also shown in the diagram, allowing easy correlation and quick insights into the spectrum diagram.



SUPERIOR USER EXPERIENCE ADVANCED USABILITY, EASY DOCUMENTATION, FAST REMOTE CONTROL

Quick access to important tools

The toolbar 1 enables quick access to important tools. Choose from a variety of tools and arrange them with maximum flexibility. The main menu 2 provides access to all instrument settings. The keys 3 left of the main menu key enable activation of the desired signals and provide quick access to analog channel, math function, FFT, arbitrary waveform generator and serial bus analysis settings.

R&S®SmartGrid

Configure your individual waveform layout on the screen using the R&S[®]SmartGrid function **4**. See the fundamental signal parameters in the signal bar **5**. From here, drag&drop waveforms into the R&S[®]SmartGrid and arrange them as desired. Superimposing waveforms is also possible.



Enhanced touchability

The box design **6** implemented for all instrument settings provides enhanced touchability. Tap on any part of a box to change the value of the parameter.

Search function

Easily find any oscilloscope capability you are looking for by simply typing it into the search box **7**.

Save results fast

Save waveforms in various file formats or download them via Ethernet or USB for later analysis with MATLAB or Excel. You can also save screen content, measurement data and reports.

Documentation					
Contents	waveform	complete			
		selection (zoom, cursor, gate, manual)			
		number of acquisitions			
		history memory			
		measurement results			
Format	measurement data	binary, CSV, 1 to 4 channels			
	graphics	PNG, JPG, BMP, TIF, PDF			
Drivers		VXI, LabVIEW, LabWindows/CVI, .NET			
Remote control		web interface, VNC, SCPI			
Languages		choose from 13			

Documentation at the press of a key

Document your measurements quickly:

- Screenshots including waveforms and results
- Clear grid annotations for easy-to-read signal characteristics
- Color-coded labeling to highlight signal portions of interest, e.g. anomalies
- Save waveforms and measurement results in binary or CSV format for signal analysis on a PC

Remote control access: anytime, anywhere

Remotely control your MXO 4 and view the display on a PC or mobile device. View the same user interface as on the instrument itself. All oscilloscope functions are also available remotely via Ethernet or USB.

Language selection

The MXO 4 series user interface supports multiple languages. Just a few seconds are needed to switch languages while the instrument is running, making the oscilloscope truly international.

Search Q	Search Q	Search Q	Search Q	Search Q
√. 垂直軸	∿. Vertical	∿. 수직	∿‡ Vertikal	∿! 垂直
◇ 水平軸	ڬ Horizontal	🛆 수평	🔆 Horizontal	🛆 水平
ブートリガ	ૐ Déclenchem…	🎢 트리거	🥕 Trigger	▶ 触发
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☆ カーソル	∱\ Curseur	☆ 커서	🔨 Cursor	☆ 光标
LLM スペクトラム	اللہ Spectre	ມ 스펙트럼	<u> </u>	山 频谱
f(x) 演算	f(x) Math	f(x) 연산	f(x) Math	f(x) 运算
Apps	Apps	*** 앱	Apps	Apps
薺 ロジック	薺 Logique	奕 로직	盔 Logik	涇 逻辑
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+ ≡ Spec Gen x=⊐-	+ Spec Gen <mark>∭</mark> Menu	+ Spec Gen 메뉴	+ Spec Gen <mark>Menü</mark>	+ ☴ Spec Gen 菜单

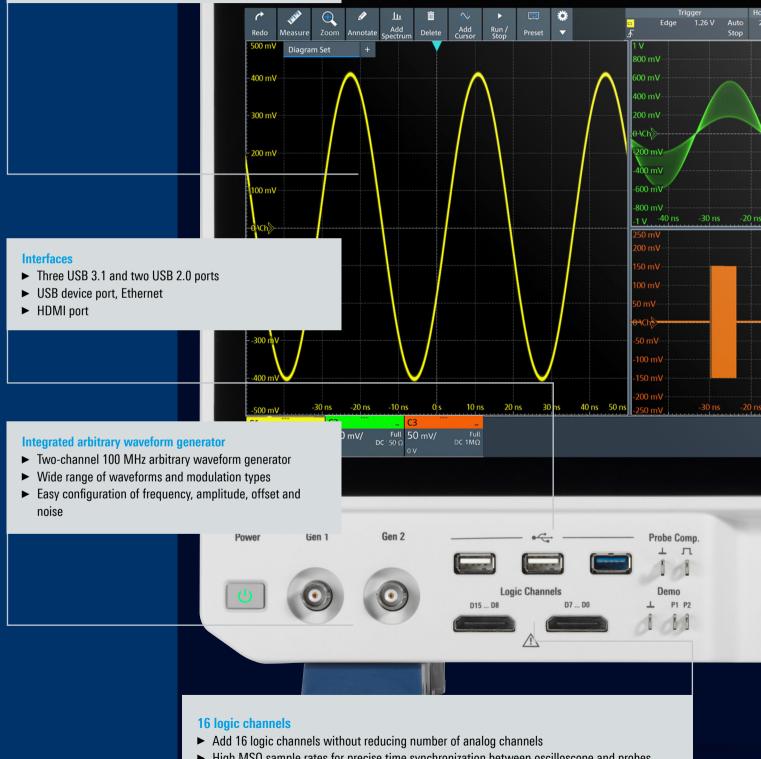


ENHANCED USABILITY

13.3" high resolution, multitouch display

- High resolution: 1920×1080 pixel (Full HD) ►
- Gesture support speeds up scaling and zooming ►
- ► Easy-to-see signal details





► High MSO sample rates for precise time synchronization between oscilloscope and probes

Intuitive front panel design for efficient operation

- ► Fast, direct access to primary instrument settings
- Quickly adjust settings with knobs and keys
- Sectional layout makes finding the right function easy



C1









\frown C1–C4, Trigger In: 1 M Ω : \leq 300V RMS, \leq 400 V pk; 50 Ω : \leq 5V RMS

Active probe interfaces

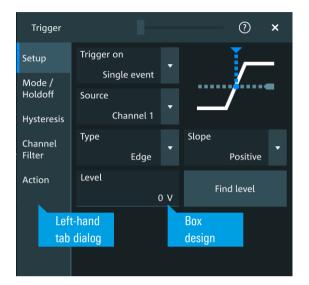
- ► Support for over 30 Rohde & Schwarz current and voltage probes
- 50 Ω and 1 M Ω path enable support of an even wider range of passive and active probes, including ones from third parties

FUN TO DRIVE 15-MINUTE LEARNING CURVE, ENHANCED TOUCHABILITY, INTUITIVE NAVIGATION

Superior usability

Extensive user feedback and research into smart device user interface concepts led to the development of the MXO 4 series user interface:

- The main menu key in the lower right corner of the touchscreen opens a pull-up menu that provides access to all of the oscilloscope's functions. The main menu is positioned within easy reach of the front panel, so that users can quickly switch between the touchscreen and the front panel controls
- The left-hand tab dialogs produce small areas, maximizing the waveform viewing area
- ▶ Box design to touch anywhere in a large target area
- The keys in the signal bar on the lower left make it easy to turn on/off signal sources and to adjust the R&S[®]SmartGrid layout
- Unique in the industry is the toolbar for quick access to your favorite tools
- The toolbar can be personalized. lcons, e.g. for measurement, cursors and spectrum display, can be rearranged, added or removed
- Fast one-touch access to trigger setup, horizontal settings and acquisition control directly from the menu bar on the upper right
- Select the icon with the Rohde&Schwarz logo to see current instrument details including LAN IP and firmware version
- The user interface is consistent with that of the R&S®RTO6 and R&S®RTP oscilloscopes (see photos below)





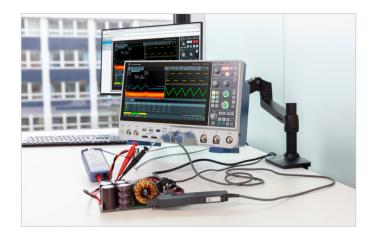




YOUR GO-TO TOOL READY FOR MANY USES

An oscilloscope as flexible as you

Need additional test capability? Customize your MXO 4 series oscilloscope with the application software and probes that your applications need.



Need digital channels?

Add 16 digital channels with the R&S®MXO4-B1 mixed signal option (MSO). Unlike some other oscilloscopes that force a tradeoff between digital and analog channel usage, the MXO 4 series digital channels can be used simultaneously with all analog channels. Simply connect the required R&S®MXO4-B1 probes (one or two) to the MXO 4 to use the digital channels.



Need configurable waveform generation?

With the R&S®MXO4-B6 arbitrary waveform generator option, you can add two integrated 100 MHz arbitrary waveform generators. Waveforms captured on the oscilloscope can be replayed by the generator and noise can be added to create worst case performance to determine system tolerance. Select from a wide range of available waveshapes or load an arbitrary waveform.

Choose from a wide selection of compatible probes

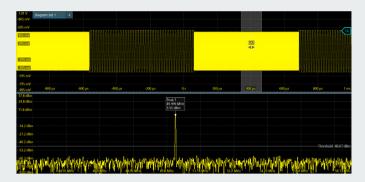
Rohde & Schwarz provides a broad portfolio of current and voltage probes. All MXO 4 series oscilloscope channel inputs include a Rohde & Schwarz probe interface connection for Rohde & Schwarz active probes. Many third-party probes are also compatible with the instrument.



EMI DEBUGGING

Easy navigation in frequency domain

The MXO 4 spectrum function has the familiar interface of a spectrum analyzer. The spectrum measurement setup dialog offers basic spectrum analyzer parameters such as start and stop frequency and resolution bandwidth. In spectrum mode, the MXO 4 time domain settings are unaffected. This makes navigation in the frequency domain an easy task. The maximum FFT capture bandwidth corresponds to the MXO 4 series bandwidth, allowing a quick overview of all of a DUT's emissions from 0 Hz to 1.5 GHz.



Gated spectrum for correlated time and frequency analysis

With the gated spectrum function, it is possible to restrict spectrum analysis to a user-defined region of the captured time domain signal. Excessive spectral emissions can be correlated to dedicated time periods in a signal. Typical applications include the correlation of unwanted emissions with fast switching edges in switched-mode power supplies or with data transfers on bus interfaces. Having identified the problem, the design engineer can easily check the effectiveness of remedies such as blocking capacitors or reduced rise/fall times by observing the level change of the spectral emission.

Ultra-fast spectrum acquisitions for detecting random and spurious spectrum events

The MXO 4 series architecture is optimized in terms of hardware and software to leverage the powerful MXO-EP ASIC capabilities to deliver fast and responsive spectrum captures. This is critical in detecting random and spurious emissions that are otherwise hidden due to the blind time in oscilloscope acquisitions. Spectrum analysis includes max. hold, min. hold and average functionality to keep track of spectrum events that occur during testing. These important test receiver functions come standard with the MXO 4 series spectrum function.

The right setup with the right probes

Rohde & Schwarz offers the compact R&S®HZ-15 near-field probe set, which is particularly helpful for EMI debugging of embedded designs. The most compact probe in this set allows capturing near-field emissions from single circuit lines. The R&S®HZ-15 covers the frequency range from 30 MHz to 3 GHz. With reduced sensitivity, it can also be used below 30 MHz. The optional R&S®HZ-16 preamplifier provides 20 dB gain in the frequency range from 100 kHz to 3 GHz, in case higher sensitivity is needed.





LOGIC ANALYSIS

Logic analysis enabled by default

The MXO 4 series oscilloscopes have the R&S®MXO4-B1 mixed signal option (MSO) hardware built into every instrument. The MSO option provides the logic probes required for using the 16 digital channels.

See more signal details with fast sample rate and deep memory

With a sample rate of 5 Gsample/s, the MXO 4 series oscilloscope provides high time resolution of 200 ps for all digital channels. This sample rate is available over the entire memory depth of 400 Mpoints per channel. The mixed signal option offers comprehensive trigger capabilities to detect critical events such as narrow glitches or certain logical patterns.



Analysis of low speed serial buses with digital channels

Today, high speed interfaces are often combined with low speed control or programming buses in a single device. You can use the digital channels of the R&S[®]MXO4-B1 option to trigger and decode low speed serial protocols such as SPI and I²C with the appropriate protocol options. All protocol analysis tools for the analog channels, such as decode table and search, are also available for the digital channels. Trigger on protocol details such as start, address and data in order to focus on dedicated events.

Diagram Set 1	•	<u> </u>	:863.5 µs			ςu1 ΔY:14.17 mV
\sim				<u>hiji sa dhurete sa sa </u>		
-SB1 SPI MOSI	4 90 8 H	MOSI A 0 8A 4E 6 (28 CA 0 3 A 71 D C h h A h h f D 3 h	SC 8 2 8A 8C 2 2 h 0 8 h h 7 7	6 4 80 4 C h		
D0						
D1						
<mark>D2</mark> -525 μs -400 μs	-200 μs 0 s	200 μs 400 μs	600 μs 8	00 μs 1 n	ns 1.2 ms	1.48 ms
Index State Star	t Count MOSI values	MISO valı SPI details	C1 X1 41.638139 μs Χ	(2 905.12474 μs	Y1: 5.4 mV	Y2: 19.5 mV
	499 μs 0 489D ADOC 8 506 0 28 8A8C 272	··· Index MOSI MIS	io	1/dx: 1.1580956 kHz	dy: 14.2 mV	4y/dx: 16 V*Hz

SERIAL BUS ANALYSIS

Dual-path protocol analysis

With the MXO 4 series, you can experience protocol analysis innovation. Traditional oscilloscopes typically capture data packets in the decoding path using the same sample rate as in the waveform path.

The MXO 4 series offers dual-path protocol analysis. You can set the instrument sample rate for the waveform path, and the oscilloscope will automatically use another internal decoupled sample rate for the decoding path. Even with very slow sample rates, the protocol data is correctly decoded. With conventional oscilloscopes, decoding would not be possible due to undersampling.



Capture more data packets with deep memory

Need to capture long time periods? You can use the MXO 4 series extended memory to capture more data packets. With a memory depth of up to 800 Mpoints, the MXO 4 can capture long periods of time where causes and effects are widely apart. During the entire capture, signal details are time-correlated with packet content for fast debugging.

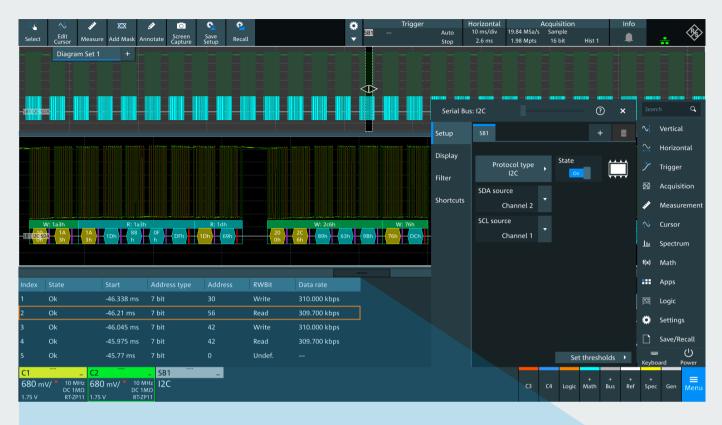
					Write	310.000 kbps
		-47.034 ms			Read	309.700 kbps
		-46.869 ms			Write	310.000 kbps
	Ok	-46.799 ms	7 bit	42	Read	309.700 kbps
		-46.594 ms			Undef.	
			10 bit		Write	443.800 kbps
		-46.305 ms			Write	310.000 kbps
					Write	442.400 kbps
		-46.159 ms	10 bit		Read	442.900 kbps
		-45.99 ms			Read	310.000 kbps
		-45.885 ms			Write	442.900 kbps
					Write	309.700 kbps
		-45.609 ms			Write	442.400 kbps
1		-45.503 ms			Read	443.400 kbps
I2C det	ails					
Index	Value	Ack start	Ack bit			
1	EBh	-46.738 ms	Ack			
2	56h	-46.705 ms	Ack			
	DBh	-46.672 ms	Ack			
		-46.639 ms	No ack			

Trigger and decode packages

Option	Description	Buses
R&S®MXO4-K500	bus analysis	
R&S®MXO4-K510	low speed serial buses	I ² C/SPI/RS-232/RS-422/RS-485/UART/QUAD-SPI
R&S®MXO4-K520	automotive buses	CAN/CAN FD/CAN XL/LIN/SENT
R&S®MXO4-K530	aerospace protocols	ARINC 429/MIL-STD-1553
R&S®MXO4-K550	MIPI low speed protocols	SPMI/REFE/I ³ C
R&S®MXO4-K560	automotive Ethernet buses	10BASE-T1S

Individual screen setup

Zoom in and out on the decoded protocol data using the vertical and horizontal control knobs or using your fingers on the touchscreen. Use the R&S[®]SmartGrid function to rearrange the windows displayed on the screen to best fit your viewing preferences. The decoded bus data can be overlaid on the captured signal and/or displayed in a separate window.



Index	State	Start	Address type	Address	RWBit	Data rate
1	Ok	-46.338 ms	7 bit	30	Write	310.000 kbps
2	Ok	-46.21 ms	7 bit	56	Read	309.700 kbps
3	Ok	-46.045 ms	7 bit	42	Write	310.000 kbps
4	Ok	-45.975 ms	7 bit	42	Read	309.700 kbps
5	Ok	-45.77 ms	7 bit	0	Undef.	
C1		C2	_ SB1	-		
680 m	V/ [▲] 10 MHz DC 1MΩ	680 mV/ 10 M	120			
1.75 V		1.75 V RT-ZP				

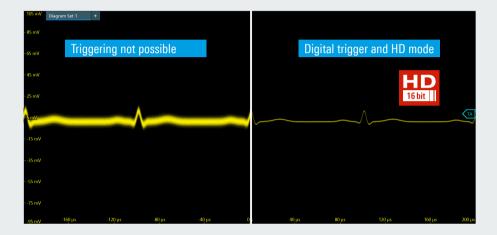
POWER ANALYSIS

See power signal details with up to 18 bit resolution

Even the smallest signal details of a highly dynamic signal matter for power measurements, for example when verifying $R_{DS(on)}$ for a MOSFET. The HD mode of the MXO 4 series oscilloscope increases the vertical resolution up to 18 bit so that previously unseen signal details become visible and can be measured. The oscilloscope also offers adjustable digital filters that allow noise suppression resulting in sharper waveforms with more signal details.

Digital trigger for enhanced debugging capabilities

With up to 18 bit vertical resolution, the MXO 4 series digital trigger architecture enables triggering on the smallest vertical variation sampled. The MXO 4 trigger system offers sensitivity of 0.0001 div and is adjustable to factor in different trigger requirements, for example to avoid false triggering on noise. It is also possible, with the digital trigger, to adapt the filter cutoff frequency only on the trigger path while maintaining the original waveform for viewing and measurements.



Maintaining fast sample rates with deepest memory

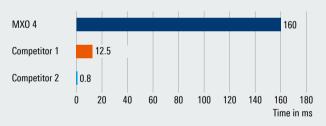
Analyzing power up/power down and transient behavior of power supplies requires high sample rates and long recording times. With up to 800 Mpoints of memory, highest in its class, the MXO 4 series oscilloscope can record long periods of time while maintaining high sample rates of up to 5 Gsample/s.

Extensive probe portfolio: high voltage and current probes

The Rohde&Schwarz portfolio of high voltage probes includes active differential probes for voltage up to 6000 V (peak). These probes offer exceptional common mode rejection over a broad frequency range. Rohde&Schwarz current probes enable accurate, non-intrusive measurements of DC and AC current. Different models are available to measure current in the range from 1 mA to 2000 A with a bandwidth of up to 120 MHz.

The R&S®RT-ZISO isolated probing system can withstand high common mode voltage levels of up to 60 kV and excellent common mode rejection at 1 GHz. With input range from 20 mV to 3 kV, it is another great probe addition for power measurements.

Acquisition time (at 5 Gsample/s)





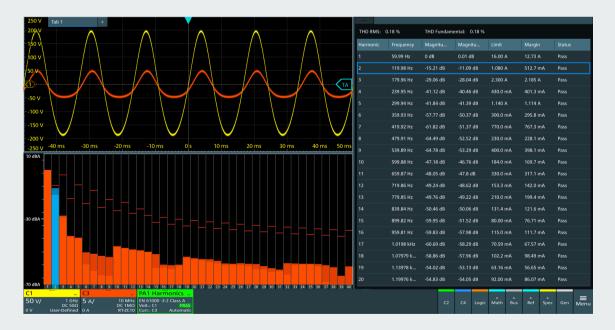
Characterizing input power quality

Measuring AC circuit power quality can be tedious due to the numerous calculations required to determine the real, apparent and reactive power. An oscilloscope is ideal for this work because it provides a clear view of the wave-form characteristics between voltage and current, allowing engineers to quickly identify and resolve problems. The R&S®MXO4-K31 enables power quality measurements and provides concurrent analysis of three pairs of voltage and current sources.



Harmonic current analysis in line with standards

Different standards for limiting the harmonic current must be met in AC power supplies. Identifying distortion from harmonic content is tedious without a proper tool. The R&S®MXO4-K31 includes current harmonic analysis to help test in line with all common standards. Users can setup three concurrent harmonic measurements.



R&S®MXO4-K31 power analysis option

Power quality

Current harmonics

active, apparent and reactive power, crest factor and phase angle

THD RMS and fundamental functions, in line with EN 6100-3-2 classes A, B, C, D, MIL-STD-1399 and RTCA DO-160

More analysis functions to be added in future.

FREQUENCY RESPONSE ANALYSIS

Creating Bode plots with the MXO 4 series

Perform low frequency response analysis

The R&S®MXO4-K36 frequency response analysis (FRA) option lets you perform low frequency response analysis on your oscilloscope easily and quickly. It measures the frequency response of a variety of electronic devices, including passive filters and amplifier circuits. For switched-mode power supplies, it measures the control loop response (CLR) and power supply rejection ratio (PSRR).

The FRA option uses the oscilloscope's built-in arbitrary waveform generator to create stimulus signals in the range from 10 mHz to 100 MHz. Measuring the voltage ratios of the stimulus signal and the output signal of the DUT at each test frequency, the oscilloscope plots gain and phase logarithmically.



Features and functionalities

Amplitude profiles

The R&S[®]MXO4-K36 allows users to configure amplitude profiles for the generator output level. This helps optimize signal-to-noise ratio (SNR) at different frequencies when measuring CLR and PSRR. Users can also load lookup tables for generator settings.

Improved resolution and marker support

Users can define the number of points per decade to set the required resolution and sweep time. Markers can be placed on the traces with a table showing the corresponding parameter values. An auto placement function makes it easy for users to determine the phase and gain margin.

Parallel display of time domain

Parallel display of time and frequency domain allows users to monitor if an injected signal causes distortion that leads to measurement errors. These effects are hard to spot from just the Bode plot. Using the time domain window together with the Bode plot significantly facilitates adjusting the amplitude profile to the optimal level.

Result table

The measurement result table displays the frequency, gain and phase shift for each measured point. The markers and result table provide interactive display of the selected information. For reporting purposes, screenshots, result table or both can be saved to a USB device.

Broad probe portfolio

Accurate CLR and PSRR characterization depend on the right probes, since the peak-to-peak amplitudes of both the input and output voltage can be very low at some test frequencies. These small amplitudes could be buried in the oscilloscope noise floor and in the DUT switching noise. We recommend the low-noise R&S®RT-ZP1X 38 MHz bandwidth 1:1 passive probes that reduce attenuation errors and have the best SNR.



R&S®MXO4-K36 frequency response analysis option					
10 mHz to 100 MHz					
fixed or amplitude profile					
10 mV to 10 V into high Z; 5 mV to 5 V into 50 Ω					
10 points to 500 points per decade					

DEBUGGING POWER RAILS AND SWITCHING CHARACTERISTICS

Debugging and characterizing power rails

Accurately measure ripple and PARD

The MXO series excels in precise measurements of power noise and ripple. The low noise capability ensures accurate power integrity measurements, even at the millivolt level. The oscilloscope stands out with a fast update rate and the unique FreeRun triggering feature for quick identification of infrequent and worst-case ripple, as well as periodic and random disturbance (PARD) anomalies. The uncompromised automatic measurements of the MXO facilitate faster statistic correlation through rapid acquisition. The oscilloscopes also offer high offsets of ± 5 V at the highest sensitivity, making them suitable for basic power integrity measurements even with 10x passive probes.



Characterizing power transistor switching behavior

Newer technologies in fast power MOSFET, IGBT and wide bandgap (WBG) devices require a closer look at transistor switching behavior to improve overall system efficiency with better timing control. The digital trigger in the MXO series enables precise triggering with hysteresis control that helps prevent false event detection. The ABR sequential trigger with 0 delay timing available between events also enables complex trigger setups that would not be possible without the digital trigger architecture. The 18-bit HD mode and the zone trigger give the MXO excellent event detection even in noisy environments.



Power rail characterization with high fidelity probes

The R&S®RT-ZPR probe is an excellent for accurate power rail characterization with high bandwidth, sensitivity, low noise and large offset compensation capabilities. A bandwidth of up to 2 GHz, sensitive down to a 1:1 attenuation ratio and low noise performance make the R&S®RT-ZPR probe ideal for precise ripple measurements. Combined with the probe's advanced frequency analysis capabilities, periodic and random disturbances (PARD) are effectively isolated. Furthermore, the probe has a high-precision, 18-bit DC voltmeter (R&S®ProbeMeter) for instant DC voltage readout, enhancing measurement accuracy.



Safety with isolation and high CMRR measurements

The R&S®RT-ZISO isolated probing system is designed for measurement challenges in high voltage and fast switching environments. The power-over-fiber architecture galvanically isolates the device under test (DUT) from the measurement setup for the highest common mode rejection ratio (CMRR) up to 1 GHz. The probe works seamlessly with the MXO series and is useful when characterizing high-side gate switching, where fast and high voltage transitions in the source node generate fast common signals. The probe can also be applied to high bandwidth current sensing over a series shunt resistor.



INTEGRATED ARBITRARY WAVEFORM GENERATOR

Compact and configurable

Two-channel 100 MHz arbitrary waveform generator

Equipped with the R&S®MXO4-B6 option, the MXO 4 oscilloscope offers a fully integrated two-channel 100 MHz arbitrary waveform generator. With up to 625 Msample/s and 16 bit resolution, the generators are suitable for implementing prototype hardware and for educational purposes. The integrated generators provide both standard and arbitrary waveforms as stimulus signals to the DUT. They can be operated as function and/or modulation generators and also support the sweep mode.

Wide range of waveforms and modulation types

The integrated arbitrary waveform generators deliver sine, square/pulse, ramp, triangle, sine cardinal (sinc), arbitrary and noise waveforms as stimulus signals to the DUT. For all waveforms, you can set the frequency, amplitude, offset and noise and also add bursts.

The modulation feature supports AM, FM, FSK and PWM modulations for sine, rectangle, triangle and ramp waveshapes.



R&S®MXO4-B6 arbitrary waveform generator option					
Analog output	2 channels				
Bandwidth	100 MHz				
Amplitude	high impedance: 10 mV to 10 V (peak-to-peak), 50 Ω: 5 mV to 5 V (peak-to-peak)				
Arbitrary waveform length	1 sample to 40 Msample per channel				
Sample rate	1 sample/s to 312.5 Msample/s				
Vertical resolution	16 bit				
Operating modes	 function and arbitrary waveform generator (DC, sine, square/pulse, triangle, ramp, inverse ramp, sinc, arbitrary) modulation (AM, FM, FSK, PWM) frequency sweep noise 				

R&S®ScopeStudio SOFTWARE

Oscilloscope application software for PCs: Enhance your oscilloscope experience

An MXO series oscilloscope for your PC

Take your oscilloscope analysis to the next level with R&S®ScopeStudio software. The powerful tool lets you view, analyze, document and share measurements on a PC – when you are away from your oscilloscope. The intuitive MXO series graphical user interface helps efficiently create professional documentation with the flexible R&S®SmartGrid layout, a wide variety of built-in annotation capabilities and a customizable toolbar.

Acquire once, replay forever

Ever wish to easily access captured oscilloscope waveforms and measurement data when you were away from the instrument? Now you can. Take time for analysis, far from noisy labs and free up the oscilloscope for others. Explore the vast set of MXO series oscilloscope measurement and analysis capabilities, add documentation notes or save information to your local PC or network drive. You can do all this while still acquiring new measurements remotely, thanks to the MXO web interface.

Oscilloscope application software for PCs

MXO series oscilloscope



PC running R&S[®]ScopeStudio software



Easy to view, analyze and measure

R&S®ScopeStudio has the same comprehensive measurement and analysis as MXO series oscilloscopes. You can apply identical measurements and analysis to captured waveforms. You can also seamlessly continue your work on a PC by loading saved sessions, instrument settings and waveforms.

Quickly share and document

Ever need to remotely collaborate within your company or with external partners, suppliers or customers? Since R&S[®]ScopeStudio runs on your PC, collaboration is easy with file sharing and PC tools.

Key facts

- ▶ PC based analysis of oscilloscope waveforms
- Advanced signal processing and visualization capabilities
- Customizable R&S[®]SmartGrid layout for efficient analysis
- Seamless integration and compatibility with MXO series oscilloscopes

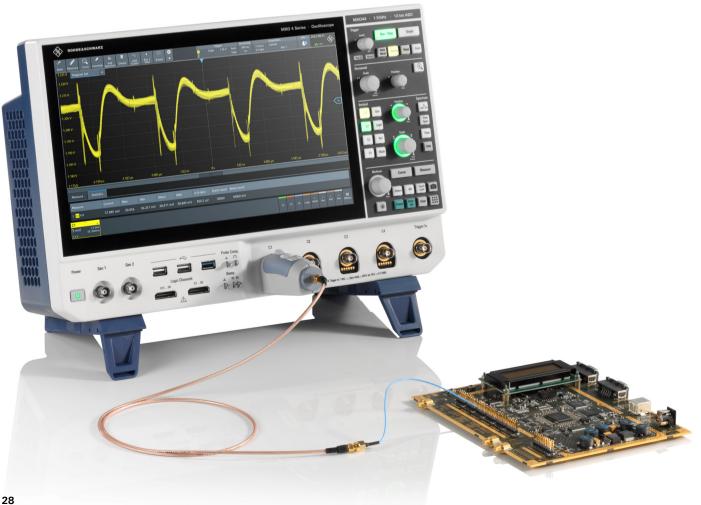
EXTENSIVE PROBE PORTFOLIO THE RIGHT PROBE FOR THE BEST MEASUREMENT

Extensive range of probes for all measurement tasks

A complete portfolio of high-quality passive and active probes covers all measurement tasks. With an input impedance of 1 M Ω , the active probes only put a minimum load on the signal source operating point. The active single-ended probes offer a very wide dynamic range, e.g. 60 V (V_{nn}) at 1 GHz, even at high frequencies, preventing signal distortion.

Complete portfolio for power measurements

The portfolio of dedicated power measurement probes includes active and passive probes for different voltage and current ranges – from μA to kA and from μV to kV. Dedicated power rail probes help detect even small and sporadic distortions on DC power rails.



Micro button for convenient instrument control

The situation is familiar to every engineer: You have carefully positioned the probe on the DUT and you want to start measuring, but you do not have a free hand. The micro button on Rohde&Schwarz active probes solves the problem. It is conveniently located close to the probe tip, and you can assign it different functions such as run/stop, autoset and adjust offset.

High voltage differential probes

The R&S[®]RT-ZHD series high voltage differential probes provide an excellent common mode rejection ratio (CMRR) over a wide bandwidth of up to 200 MHz and can safely measure up to 6000 V peak voltages. These probes exhibit exceptionally low noise, making them ideal for switching power analysis.

Like all active probes from Rohde&Schwarz, the R&S®RT-ZHD probes are equipped with the R&S®ProbeMeter, a high-precision DC voltmeter offering 0.1% accuracy while ensuring 0.5% gain accuracy and very low measurement drift. They also have an integrated 5 MHz analog filter, an audible common mode voltage overrange indicator and a micro button to give users full awareness of and control over the probe measurements.





High voltage differential probes for switching power analysis measurements.

Rohde & Schwarz has a comprehensive probe portfolio to meet every probing need.

For more information, see product brochure "Probes and accessories for Rohde&Schwarz oscilloscopes" (PD 3606.8866.12)



Passive probes included as standard (38 MHz to 700 MHz) R&S°RT-ZP11, R&S°RT-ZP1X



Passive broadband probes (8 GHz) R&S®RT-ZZ80 Passive probes come standard with every Rohde&Schwarz oscilloscope. They are low cost, general purpose probes for a broad range of applications.

These are an economical yet powerful alternative to active probes for measuring high speed signals on low impedance lines. Their input impedance is low and remains practically constant over the entire bandwidth. They feature extremely low input capacitance, very low noise and high linearity.



Active single-ended broadband probes (1 GHz to 6 GHz) R&S°RT-ZS10E, R&S°RT-ZS10, R&S°RT-ZS20, R&S°RT-ZS30, R&S°RT-ZS60 A very high dynamic range and exceptionally low offset and gain errors combined with the right accessories make these probes ideal for Rohde & Schwarz oscilloscopes.



Active differential broadband probes (1 GHz to 4.5 GHz) R&S°RT-ZD10, R&S°RT-ZD20, R&S°RT-ZD30, R&S°RT-ZD40 and R&S°RT-ZA15 external attenuator

A flat frequency response and high input impedance with low input capacitance permit precise measurements on differential signals while maintaining a low load on the DUT. The CMMR for the entire probe bandwidth has high interference immunity. Special browser adapters allow flexible contacting with high signal fidelity.



Power rail probes (2 GHz and 4 GHz) R&S®RT-ZPR20, R&S®RT-ZPR40 Wide bandwidth, high sensitivity, very low noise and extra-large DC offset make these probes an excellent tool for characterizing power rails. The integrated high-precision DC voltmeter (R&S®ProbeMeter) provides instantaneous DC voltage readout.



High voltage probes (100 MHz to 400 MHz; ±750 V to ±6000 V) R&S°RT-ZH03, R&S°RT-ZH10, R&S°RT-ZH11, R&S°RT-ZD01, R&S°RT-ZHD07, R&S°RT-ZHD15, R&S°RT-ZHD16, R&S°RT-ZHD60



Current probes

(20 kHz to 120 MHz; ±1 mA to ±2000 A) R&S°RT-ZC02, R&S°RT-ZC03, R&S°RT-ZC05B, R&S°RT-ZC10, R&S°RT-ZC10B, R&S°RT-ZC15B, R&S°RT-ZC20, R&S°RT-ZC20B, R&S°RT-ZC30, R&S°RT-ZC31



EMC near-field probes (30 MHz to 3 GHz) R&S®HZ-15, R&S®HZ-17 The Rohde&Schwarz portfolio of high voltage probes includes passive single-ended and active differential probes for voltages up to 6000 V (peak). Different models allow measurements in up to CAT IV environments. Differential probes provide exceptional common mode rejection over a wide bandwidth.

Rohde & Schwarz current probes enable accurate, non-intrusive measurements of DC and AC currents. Different models are available to measure currents in the range from 1 mA to 2000 A with a bandwidth of up to 120 MHz. Current probes are available with the Rohde & Schwarz probe interface or a BNC connector for an external power supply.

Powerful E and H near-field probes for the frequency range from 30 MHz to 3 GHz with an optional preamplifier expand the application range of the MXO 4 series oscilloscope to include EMI debugging.

AND THERE IS SO MUCH MORE ... AN OSCILLOSCOPE THAT EVOLVES WITH YOUR NEEDS

Grows with your needs - fully software based upgrades

The MXO 4 series flexibly adapts to evolving requirements for your project. The MXO 4 oscilloscopes come equipped with all hardware and software options. To enable a desired option, all you have to do is purchase a software license and activate the function or upgrade via keycode. This includes bandwidth upgrades up to 1.5 GHz, mixed signal option, memory upgrade, arbitrary waveform generator, serial bus triggering and decoding, and frequency response analysis. This makes retrofitting very easy.

Regular firmware improvements

Regular firmware updates add new functionality to the MXO 4 series oscilloscopes. Download the latest firmware version at www.rohde-schwarz.com and use a USB storage device or LAN connection for installation. This will keep your MXO 4 series oscilloscope up to date.

Multilingual support: choose among thirteen languages

The user interface and online help of the MXO 4 series oscilloscopes support thirteen languages (English, German, French, Spanish, Italian, Portuguese, Czech, Polish, Russian, Simplified and Traditional Chinese, Korean and Japanese). You can change the language in just a few seconds while the instrument is running.

Safe transport and easy rack mounting

An extensive selection of storage and transportation accessories means the MXO 4 series oscilloscopes are always fully protected and easy to transport. The rackmount kit allows easy installation of the oscilloscope in integrated environments.



Accessories	
Front cover	R&S [®] MXO4-Z1
Soft case	R&S [®] MXO4-Z3
Transit case, with trolley function	R&S [®] MXO4-Z4
19" rackmount kit	R&S [®] ZZA-MXO4
VESA mounting interface	100 mm \times 100 mm VESA standard pattern on the rear of all instruments





THE MXO SERIES



SEE THE BIG PICTURE WITH ALL THE SMALL DETAILS

SPECIFICATIONS OF BASE UNIT

Vertical system: analog channels		
Input channels		4 channels
Input impedance		$50 \Omega \pm 1.5\%$,
		1 MΩ ± 1% 12 pF (meas.)
Analog bandwidth (–3 dB)	at 50 Ω input impedance	
	MXO 4	≥ 200 MHz
	MXO 4 with -B243 option	≥ 350 MHz
	MXO 4 with -B245 option	≥ 500 MHz
	MXO 4 with -B2410 option	≥ 1 GHz
	MXO 4 with -B2415 option	\geq 1.5 GHz ¹⁾
	at 1 MΩ input impedance	
	MXO 4	\geq 200 MHz (meas.)
	MXO 4 with -B243 option	≥ 350 MHz (meas.)
	MXO 4 with -B245 option	\geq 500 MHz (meas.)
	MXO 4 with -B2410 option	\geq 700 MHz (meas.) ²⁾
	MXO 4 with -B2415 option	\geq 700 MHz (meas.) ²⁾
Additional bandwidth filters available up to instrument bandwidth		1 GHz, 500/350/200/100/50/20 MHz (meas.)
Rise/fall time (calculated)	10% to 90% at $50~\Omega$	
	MXO 4	< 1.75 ns
	MXO 4 with -B243 option	< 1 ns
	MXO 4 with -B245 option	< 700 ps
	MXO 4 with -B2410 option	< 350 ps
	MXO 4 with -B2415 option	< 234 ps
Vertical resolution		12 bit,
		up to 18 bit for high-definition (HD) mode
Effective number of bits (meas.)	at 50 Ω , 50 mV/div, with HD mode and digital filt	-
	10 MHz	10.1
	20 MHz	9.6
	100 MHz	8.7
	200 MHz	8.4
	300 MHz	8.2
	500 MHz	7.9
	1 GHz	7.3
Input sensitivity	at 50 Ω	0.5 mV/div to 1 V/div, entire analog bandwidth supported for all input sensitivities
	at 1 MΩ	0.5 mV/div to 10 V/div, entire analog bandwidth supported for all input sensitivities
DC gain accuracy	offset and position set to 0 V, after self-alignmen	t
	input sensitivity > 5 mV/div	±1% of full scale
	input sensitivity ≤ 5 mV/div to ≥ 1 mV/div	±1.5% of full scale
	input sensitivity < 1 mV/div	±2.5% of full scale
Input coupling	at 50 Ω	DC
	at 1 MΩ	DC, AC (> 7 Hz)
Maximum input voltage	at 50 Ω	5 V (RMS), 30 V (V _p)
	at 1 MΩ	300 V (RMS), 400 V (V _p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz
	at 1 $M\Omega$ with R&S°RT-ZP11 passive probe	400 V (RMS), 1650 V (V _p), 300 V (RMS) (CAT II); for derating and details, see R&S®RT-Zxx Standard Probes specifications (PD 3607.3851.22)
Position range		±5 div

 $^{\eta}$ $\,$ 1.5 GHz analog bandwidth in interleave mode with 5 Gsample/s real-time sampling rate.

²⁾ With R&S®RT-ZP11 passive probe.

Vertical system: analog channels		
Offset range at 50 Ω	input sensitivity	
	100 mV/div to 1 V/div	±20 V
	0.5 mV/div to < 100 mV/div	±5 V
Offset range at 1 $M\Omega$	input sensitivity	
	800 mV/div to 10 V/div	±200 V
	80 mV/div to < 800 mV/div	±50 V
	0.5 mV/div to < 80 mV/div	\pm (5 V – input sensitivity × position)
Offset accuracy		\pm (0.35% × net offset + 0.5 mV + 0.1 div × input sensitivity) (net offset = offset – position × input sensitivity)
DC measurement accuracy	after adequate suppression of measurement noise using high-definition (HD) mode or waveform averaging or a combination of both	±(DC gain accuracy × reading – net offset + offset accuracy)
Channel-to-channel isolation (each channel with same input sensitivity)	input frequency within instrument bandwidth	> 60 dB (1:1000)

t 50 Ω (meas.)	Input sensitivity	Analog bandwidth (–3 dB)				
		20 MHz	200 MHz	350 MHz	500 MHz	1 GHz
	0.5 mV/div	20 µV	43 µV	47 µV	50 µV	98 μV
	1 mV/div	22 µV	45 µV	50 µV	54 µV	104 µV
	2 mV/div	25 µV	52 µV	56 µV	61 µV	116 µV
	5 mV/div	43 µV	72 µV	77 µV	84 µV	152 μV
	10 mV/div	76 µV	118 µV	120 μV	131 µV	238 µV
	20 mV/div	148 µV	219 µV	219 µV	241 µV	436 µV
	50 mV/div	360 µV	508 μV	492 µV	543 µV	1.01 mV
	100 mV/div	747 μV	1.17 mV	1.19 mV	1.30 mV	2.47 mV
	200 mV/div	1.40 mV	2.13 mV	2.14 mV	2.34 mV	4.43 mV
	500 mV/div	3.47 mV	4.91 mV	4.80 mV	5.27 mV	10.13 mV
	1 V/div	6.88 mV	9.71 mV	9.47 mV	10.41 mV	19.96 mV
At 1 MΩ (meas.)	Input sensitivity	Analog bandwidth (–3 dB)				
		20 MHz	100 MHz	200 MHz	350 MHz	500 MHz
	0.5 mV/div	28 µV	40 µV	42 µV	47 µV	51 µV
	1 mV/div	28 µV	40 µV	46 µV	50 µV	53 µV
	2 mV/div	30 µV	43 µV	49 µV	54 µV	58 µV
	5 mV/div	44 µV	58 µV	67 μV	71 µV	78 μV
	10 mV/div	73 µV	92 µV	109 µV	109 µV	120 µV
	20 mV/div	138 µV	169 μV	199 µV	198 µV	218 µV
	50 mV/div	344 µV	442 µV	525 μV	529 µV	586 µV
	100 mV/div	739 µV	959 μV	1.13 mV	1.14 mV	1.24 mV
	200 mV/div	1.40 mV	1.74 mV	2.06 mV	2.07 mV	2.27 mV
	500 mV/div	3.47 mV	4.43 mV	5.22 mV	5.28 mV	5.75 mV
	1 V/div	7.11 mV	8.92 mV	10.44 mV	10.53 mV	11.49 mV
	2 V/div	13.83 mV	16.9 mV	19.87 mV	19.56 mV	21.38 mV
	5 V/div	34.84 mV	44.32 mV	52.43 mV	53.39 mV	57.97 mV
	10 V/div	57.16 mV	68.58 mV	80.66 mV	78.53 mV	85.46 mV

 $^{\scriptscriptstyle 3)}~$ HD mode active for bandwidths ≤ 500 MHz.

Vertical system: digital channels		
Input channels		16 logic channels (D0 to D15)
Arrangement of input channels		arranged in two logic probes with 8 channels each; assignment of logic probes to channels (D0 to D7 and D8 to D15) displayed on probes
Input impedance		100 kΩ \pm 2 % ~4 pF (meas.) at probe tips
Maximum input frequency	signal with minimum input voltage swing and hysteresis setting "normal"	400 MHz (meas.)
Maximum input voltage		$\pm 40 \text{ V} (\text{V}_{p})$
Minimum input voltage swing		500 mV (V _{pp}) (meas.)
Threshold groups		D0 to D3, D4 to D7, D8 to D11 and D12 to D15
Threshold level	range	±8 V in 25 mV steps
	predefined	CMOS 5.0 V, CMOS 3.3 V, CMOS 2.5 V, TTL, ECL, PECL, LVPECL
Threshold accuracy	threshold level between $\pm 4 \text{ V}$	\pm (100 mV + 3% of threshold setting)
Comparator hysteresis		normal, robust, maximum

11. 1		
Horizontal system		
Timebase range		selectable between 200 ps/div and 10 000 s/div, time per div settable to any value within range
Channel-to-channel deskew range	between analog channels	±20 ms
	between digital channels	±100 ns
Reference position		0% to 100% of measurement display area
Horizontal position range (trigger offset range)	max.	+(memory depth/current sampling rate)
	min.	–5000 s
Modes		normal
Channel-to-channel skew	between analog channels	< 100 ps (meas.)
	between digital channels	< 500 ps (meas.)
Timebase accuracy	after delivery/calibration, at +23 °C	±0.2 ppm
	during calibration interval	±1 ppm
Delta time accuracy	corresponds to time error between two edges of equal polarity on same acquisition and channel; signal amplitude greater than 5 div, measurement threshold set to 50%, vertical gain 10 mV/div or greater; rise time lower than four sampling peri- ods; waveform acquired in real-time mode	±(0.20/real-time sampling rate + timebase accuracy × reading) (peak) (meas.)

Acquisition system		
Sampling rate	analog channels (real time)	max. 5 Gsample/s on 2 channels, max. 2.5 Gsample/s on 4 channels
	analog channels (interpolated)	max. 5 Tsample/s
	digital channels	max. 5 Gsample/s on each channel
Waveform acquisition rate	max.	> 4500000 waveforms/s
Trigger rearm time	min.	< 21 ns
Memory depth ⁴⁾	standard	 400 Mpoints with 4 active channels (single capture) 400 Mpoints with 2 active channels (run continuous)
	with R&S [®] MXO4-B108 option	 800 Mpoints with 2 active channels (single capture) 800 Mpoints with 1 active channel (run continuous)
Acquisition modes	sample	middle sample in decimation interval
	peak detect	largest and smallest sample in decimation interval
	average	average value of samples in decimation interval
	number of averaged waveforms	2 to 16777215
	envelope	envelope of acquired waveforms

⁴⁾ The maximum available memory depth depends on the bit resolution of the acquired data and, therefore, on the acquisition system settings such as decimation mode, use of waveform arithmetics and high-definition (HD) mode.

Acquisition system				
Sampling modes	real-time	max. sampling rate depending on ADC		
	interpolated time	enhancement of sampling resolution by interpolation; max. equivalent sampling rate is 5 Tsample/s		
Interpolation modes		linear, sin(x)/x, sample&hold		
Fast segmentation mode	continuous recording of waveforms in ac	continuous recording of waveforms in acquisition memory without interruption due to visualization		
	max. real-time waveform acquisition rat	te > 4600000 waveforms/s		
	min. blind time between consecutive acquisitions	< 21 ns		
High-definition (HD) mode				
General description	-	The high-definition mode increases the bit resolution of waveform signals by using digital filtering, leading to reduced noise. Because of the MXO 4 series digital trigger concept, signals with higher resolution are used as inputs to the trigger.		
Bit resolution	bandwidth, at 5 Gsample/s	bit resolution		
	1 kHz to 10 MHz	18 bit		
	100 MHz	16 bit		
	200 MHz	15 bit		
	500 MHz	14 bit		
Real-time sampling rate	all models	max. 5 Gsample/s on 2 channels, max. 2.5 Gsample/s on 4 channels		
Trigger system				
Trigger sources		analog channels (C1 to C4), digital channels (D0 to D15), trigger input, serial bus		
Trigger level range		±5 div from center of screen		
Trigger modes		auto, normal, single, n single		
Trigger sensitivity		0.0001 div, from DC to instrument bandwidth for all vertical scales		
Trigger jitter	full-scale sine wave of frequency set to –3 bandwidth	3 dB < 1 ps (RMS) (meas.)		
Coupling mode	standard	same as selected channel		
	HF reject	cutoff frequency selectable from 1 kHz to 500 MHz		
	LF reject	attenuates frequencies < 50 kHz		
Trigger hysteresis	modes	auto (default setting) or manual		
	sensitivity	0.0001 div, from DC to instrument bandwidth for all vertical scales		
Holdoff range	time	100 ns to 10 s, fixed and random		
Main trigger modes				
Edge	triggers on specified edge (positive, nega			
Glitch	triggers on glitches of positive, negative of width	or either polarity that are shorter or longer than a specified		
	glitch width	200 ps to 1000 s		
Width	triggers on positive or negative pulse of s outside a specified range	pecified width; width can be shorter, longer, inside or		
	pulse width	200 ps to 1000 s		
Runt		either polarity that crosses one threshold but fails to cross rst one again; runt pulse width can be arbitrary, shorter,		
	runt pulse width	200 ps to 1000 s		
Window		triggers when signal enters or exits a specified voltage range; triggers also when signal stays inside or outside the voltage range for a specified period of time		
Timeout	triggers when signal stays high, low or ur	nchanged for a specified period of time		
	timeout	0 ps to 1000 s		
Interval	triggers when the time between two cons shorter, longer, inside or outside a specifi	secutive edges of the same polarity (positive or negative) is ed range		
	interval time	200 ps to 1000 s		

Trigger system			
Slew rate	triggers when the time required by a signal edge to toggle between user-defined upper and lower voltage levels is shorter, longer, inside or outside a specified range; edge slope may be positive, negative or either		
	toggle time	0 ps to 1000 s	
Setup & hold	triggers on setup time and hold time violations between clock and data present on any two input channels; monitored time interval may be specified by the user in the range from –100 s to +100 s around a clock edge and must be at least 200 ps wide		
Pattern	triggers when a logical combination (AND, NAND period of time shorter, longer, inside or outside a s		
State	triggers when a logical combination (AND, NAND edge (positive, negative or either) in one selected		
Advanced trigger modes			
Zone trigger	triggers on user-defined zones drawn on the displ	ау	
	source	acquired waveforms (input channels), math wave- forms (including power analysis waveforms), spectrum waveforms, XY plots	
	number of zones/areas	up to 4 zones with up to 8 areas each	
	area shapes	polygons with up to 16 points	
	area types	must intersect, must not intersect	
	combination of zones	logical combination of zones of multiple sources using Boolean expressions	
	trigger compatibility	requires sequence trigger A ⊳ zone trigger where primary A condition can be: edge, glitch, width, runt, window, timeout, interval, slew rate, setup &hold, state, pattern	
Sequence trigger (A/B/R trigger)	triggers on B event after occurrence of A event; de interval; an optional R event resets the trigger seq		
	A event	edge, glitch, width, runt, window, timeout, interval, slew rate	
	B event	edge, glitch, width, runt, window, timeout, interval, slew rate	
	R event	edge, glitch, width, runt, window, timeout, interval, slew rate	
Serial bus trigger	optional	see dedicated triggering and decoding options in Ordering information in this product brochure	
Trigger input	input impedance	50 Ω (meas.) or 1 M Ω (meas.) 11 pF (meas.)	
	max. input voltage at 50 Ω	30 ∨ (V _p)	
	max. input voltage at 1 $\mbox{M}\Omega$	300 V (RMS), 400 V (V_p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz	
	trigger level	±5 V	
	sensitivity		
	input frequency ≤ 500 MHz	300 mV (peak-to-peak) (meas.)	
	input coupling	AC, DC (50 Ω and 1 MΩ)	
	trigger filters	HF reject (attenuates frequencies > 50 kHz, LF reject (attenuates frequencies < 50 kHz), noise reject	
	trigger modes	edge (positive, negative or either)	
	functionality	A pulse is generated for each event triggering signal acquisition.	
Trigger output		orginal acquioritoriti	
Trigger output	output voltage	0 V to 5 V (nom.) at high impedance, 0 V to 2.5 V (nom.) at 50 Ω	
Trigger output	output voltage pulse width	0 V to 5 V (nom.) at high impedance,	
Trigger output		0 V to 5 V (nom.) at high impedance, 0 V to 2.5 V (nom.) at 50 Ω	

Spectrum analysis			
General description	Spectrum analysis allows signal analysis in the free	quency domain.	
Spectrum	sources	channel 1, channel 2, channel 3, channel 4	
	setting parameters	center frequency, frequency span, resolution bandwidth (automatic or manual), gate position, gate width, vertical scaling, vertical position	
	scaling	dBm, dBV, dBµV, V (RMS)	
	span	1 Hz to 1.8 GHz ⁵⁾	
	resolution bandwidth (RBW)	$span/4 \ge RBW \ge span/6000$	
	windows	flat top, Hanning, Hamming, Blackman, rectangular, Kaiser Bessel, Gaussian	
	trace types	normal, max. hold, min. hold, average	
	max. real-time waveform acquisition rate	> 40 000 waveforms/s	
Gate	delimits the display region used for spectrum analy	ysis	
Peak list	The values in the peak list are also shown in the di	agram to allow easy correlation.	
RF characteristics			
Sensitivity/noise density	at 1 GHz (measurement of power spectral density at 1 GHz at input sensitivity 2 mV/div, corresponding to –30 dBm input range of the oscilloscope, using spectrum analysis with center frequency 1 GHz, span 500 kHz, RBW 3 kHz)	–160 dBm (1 Hz) (meas.)	
Noise figure	at 1 GHz (calculated based on the noise power density above)	14 dB (meas.)	
Dynamic range	measured for a 1 GHz input carrier with level –3 dBm at input of oscilloscope, using spectrum analysis with center frequency 1 GHz, span 2 MHz, RBW 400 Hz at +20 MHz from center frequency	106 dB (meas.)	
Absolute amplitude accuracy	0 Hz to 1.2 GHz	±1 dB (meas.)	
Spurious-free dynamic range (excluding harmonics)	measured for a 250 MHz input carrier with level –3 dBm at input sensitivity 50 mV/div, using spectrum analysis with center frequency 900 MHz, span 1.8 GHz, RBW 300 kHz	65 dBc (meas.)	
Second harmonic distortion	measured for a 250 MHz input carrier with level –3 dBm at input sensitivity 50 mV/div, using spectrum analysis with center frequency 900 MHz, span 1.8 GHz, RBW 300 kHz	–60 dBc (meas.)	
Third harmonic distortion	measured for a 250 MHz input carrier with level –3 dBm at input sensitivity 50 mV/div, using spectrum analysis with center frequency 900 MHz, span 1.8 GHz, RBW 300 kHz	–59 dBc (meas.)	
Moveform measurements			
Waveform measurements	measurements on acquired waveforms (input channels), math waveforms, reference waveforms	amplitude, high, low, maximum, minimum, peal to-peak, mean, RMS, sigma, positive overshoot, negative overshoot, area, rise time, fall time, pos- tive pulse width, negative pulse width, period, frequency, positive duty cycle, negative duty cycle, delay, phase, burst width, pulse count, edge count, pulse train, positive switching, nega- tive switching, cycle area, cycle mean, cycle RMS, cycle sigma, setup, hold, setup/hold time, setup/hold ratio, slew rate rising, slew rate fallin delay to trigger	
	gate	delimits the display region evaluated for auto- matic measurements	
	reference levels	user-configurable vertical levels define support structures for automatic measurements	
	statistics	displays maximum, minimum, mean, standard deviation and measurement count for each auto matic measurement	
	number of active measurements	16	

Waveform measurements				
Cursor measurements	available cursors	up to two cursor sets on screen, each set with two horizontal and two vertical cursors		
	target waveforms	acquired waveforms (input channels), math wave forms, reference waveforms, XY diagrams		
	operating modes	vertical measurements, horizontal measurements or both; vertical cursors either placed manually or locked to waveform		
Manafarma madi				
Waveform math General features	such as of moth countings	un to F		
General features	number of math equations	up to 5		
	number of reference waveforms	up to 4		
	sources	channel 1, channel 2, channel 3, channel 4, math waveforms 1 to 4, reference waveforms 1 to 4		
Functions	operators	add, subtract, multiply, divide, absolute value, square, square root, integrate, differentiate, log ₁₀ , log _e , log ₂ , reciprocal, invert, lowpass, highpass, rescale (a*x+b)		
	filters	lowpass, highpass		
	filter types	Gaussian, rectangular		
	gate	delimits the display region used for waveform maths		
Display characteristics				
Display types	Yt, XY, zoom, spectrum			
Display configuration (waveform layout)	for the desired waveforms into the R&S®S	diagram areas by dragging and dropping signal icons martGrid. Each diagram can hold any number of signals. other and later accessed via dynamic tabs (Tab 1, etc.).		
Signal icons	Each active waveform is represented by a individual vertical and acquisition settings	signal icon on the signal bar; the signal icon displays the .		
Toolbar	in a simple menu and provides access to	Enables quick access to important functions; allows direct setting of their most common parameters in a simple menu and provides access to more detailed parameter settings in the main menu. The toolbar can be individually configured to include the user's preferred tools.		
Upper menu bar	Displays trigger, horizontal and acquisition	n system settings; allows quick access to these settings.		
Main menu	Provides access to all instrument settings	in a compact menu structure.		
Axis labeling	The x-axis and y-axis are labeled with valu	The x-axis and γ-axis are labeled with values and physical unit.		
Diagram labeling	Diagrams may be individually labeled with	n a descriptive, user-defined name.		
Diagram layout	The grid, crosshair, axis labeling and diagr	am labeling can be switched on and off separately.		
Persistence	50 ms to 50 s, or infinite			
Zoom	vertical and horizontal; touch interface sim	vertical and horizontal; touch interface simplifies resize and drag operations on zoom window		
Signal colors (waveform coding)				

History function and segmented mem	nory			
Acquisition memory	automatic	automatic setti	ng of segment size and sample rate	
	manual	user-defined se	etting of segment size and sample rate	
Memory segmentation	function	memory is divi	ded into segments for signal acquisition	
	number of segments	record length	segments ⁶⁾ (up to)	
		1 kpoints	1 048 575	
		2 kpoints	524287	
		5 kpoints	262143	
		10 kpoints	131071	
		20 kpoints	65535	
		50 kpoints	32767	
		100 kpoints	16383	
		200 kpoints	9361	
		500 kpoints	4095	
		1 Mpoints	2113	
		2 Mpoints	1056	
		5 Mpoints	427	
		10 Mpoints	213	
		20 Mpoints	106	
		50 Mpoints	41	
		100 Mpoints	20	
		200 Mpoints	9	
		400 Mpoints	4	
		800 Mpoints 7)	2	
	Segmentation is available tanalysis.	for all analog and digita	al channels, protocol decoding and spectrum	
Fast segmented mode	continuous recording of waveforms in acquisition memory without interruption d for blind time between consecutive acquisitions, see "Acquisition system"			
History mode	function		de is an always-on function and provides access to ns in the segmented memory.	
	timestamp resolution	1 ns		
	history player		ed waveforms; repetition possible; adjustable speed ing to next/previous segment; numerical segment	
	analysis options	overlay all segr	nents, average all segments, envelope all segment	
Mask testing				
Test definition	number of masks		up to 8 simultaneously	
	source		acquired waveforms (input channels), math wav forms, reference waveforms, spectrum wave- forms, XY plots	
	fail condition		waveform hit	
	test rate		up to 4 million waveforms/s	
	action on error		acquisition stop, beep, save waveform, pulse on trigger out, screenshot	
Mask definition with segments	number of segments per n	nask test	up to 8	
	segment definition		array of at least 3 points defines an inner region	
Result statistics	category		total completed acquisition, failed acquisition, passed acquisition, fail rate, overall test result (pass/fail)	
Visualization options	waveform style		vectors, dots	
	mask colors		predefined colors for mask without violation (translucent gray), mask with violation (translu- cent red)	

⁶⁾ With R&S®MXO4-B108 memory option. The maximum number of segments depends on the number of active channels and the bit resolution of the acquired data and, therefore, on the acquisition system settings such as decimation mode, use of waveform arithmetics and high-definition (HD) mode. The maximum number of segments without the R&S®MXO4-B108 memory option is limited to 10000. ⁷⁾ With R&S®MXO4-B108 memory option.

Miscellaneous		
Remote control	web interface	full operation of the instrument's touch interface keys and multifunction wheel via web browser
	VNC	control of the instrument through virtual networl computing
	SCPI	standard instrument programming interface through VISA
Languages	available languages for the user interface	English, German, French, Simplified Chinese, Traditional Chinese, Japanese, Russian, Spanish, Italian, Portuguese, Korean, Czech, Polish
	online help on the instrument	English
Inputs and outputs Front		
Channel inputs		BNC; for details, see "Vertical system"
	probe interface	auto detection of passive probes, Rohde&Schwarz probe interface for active probes
Trigger input		BNC; for details, see "Trigger system"
	probe interface	auto detection of passive probes
Arbitrary waveform generator outputs (requires R&S®MXO4-B6 option)		BNC; for details, see R&S®MXO4-B6 option, arbitrary waveform generator, demo lugs and GND lug
Digital channel inputs	D15 to D8, D7 to D0	interfaces for R&S®RT-ZL04 logic probe
Probe compensation output	signal shape	rectangle, V _{low} = 0 V, V _{high} = 3.3 V, amplitude 3.3 V (V _{pp}) \pm 5% (meas.)
	frequency	1 kHz ± 1% (meas.)
Ground jack		connected to ground
USB interfaces		1 × USB 3.1 Gen 1 port, type A, 2 × USB 2.0 high speed port, type A
Rear		
Trigger output		BNC; for details, see "Trigger system"
USB interfaces		2 × USB 3.1 Gen 1 port, type A, 1 × USB 3.1 Gen 1 port, type B
LAN interface		RJ-45 connector, supports 10/100/1000BASE-T
External monitor interface		HDMI, 1920 × 1080 pixel at 60 Hz, output of oscilloscope display
Reference input	connector	BNC
	impedance	50 Ω (nom.)
	input frequency	10 MHz (±20 ppm)
	sensitivity	≥ −10 dBm into 50 Ω, ≤ 10 dBm at 10 MHz
Reference output	connector	BNC
	impedance	50 Ω (nom.)
	output signal	10 MHz (specified with timebase accuracy), 8 dBm (nom.)
Security slot		for standard Kensington lock
VESA mounting interface		100 mm \times 100 mm VESA standard pattern
Right side		
Ground jack		connected to ground

Shock method no. 516.6, procedure I 30 g functional shock, half sine, duration 11 ms, in line with MIL-PRF-28800F, section 4.5.5.4.1 Electromagnetic compatibility (EMC) RF emissions Immunity Immunity Certifications Certifications VDE, cCSA _{US} , KC Calibration interval Power supply 100 V to 240 V ± 10% at 50 Hz and 400 Hz ± 5%	General data				
Temperature Operating temperature range OPC to +50°C Temperature range -40°C to +70°C in line with MILPRF-28500F, section 4.5.5.1.1.1, distance Climatic resistance damp heat in line with MILPRF-28500F, section 4.5.5.1.1.1, distance Atitude -25°C/-50°C at 95% relative hummidity, cyclic, in line with FIC00008-7.30 section 4.5.5.1.1.1, distance Atitude	Display	type			
Temperature range OPC to + 50°C storage tomperature range -40°C to + 50°C Cillmatic resistance amp beat cillmatic resistance amp beat Athiote -10°C to + 50°C Cillmatic resistance amp beat Athiote -10°C Operating up to 3000 m above sea level Nonoparating up to 4500 m above sea level Mechanical resistance		resolution	1920 × 1080 pixel (Full HD)		
Aircle of a 20°C to + 70°C in line with MILPRE 28800T, section 4.5.5.1.1, class 3, tailored to 4.5°C for operation Climatic resistance damp heet Aitude up to 3000 m above see level Nonoperating up to 3000 m above see level Nonoperating up to 3000 m above see level Mechanical resistance 5 Hr to 150 Hz, max. 1.8 g at 55 Hr; 0.5 g from 55 Hz to 150 Hz, in 160	Temperature				
in line with MLPRF-28005 section 4.5.5.1.11, class 3, tailored to 4.45°C for operation 4.25°C-50°C ct 85% indive humidity, cyclic, in line with IEC60062 2.30 Altitude up to 3000 m above sea level Mechanical resistance up to 3000 m above sea level Mechanical resistance up to 4000 m above sea level Wechanical resistance 5 Hz to 150 Hz, max, 1.8 g at 55 Hz; 0.5 g from 55 Hz to 150 Hz, in line with IEC60068-2-6 Vibration 5 insusoidal 0.5 g from 55 Hz to 150 Hz, in line with MLPRF-28000F, section 4.5.5.2, class 3 Vibration random 8 Hz to 500 Hz, max, 1.8 g at 55 Hz; 0.5 Hz to 150 Hz, in line with MLPRF-28000F, section 4.5.5.2, class 3 Shock random 8 Hz to 500 Hz, acceleration 1.2 g iRMS), in line with MLPRF-2800F, section 4.5.5.1, olass 3 Shock 40 g abock spactrum, in line with MLPRF-2800F, section 4.5.5.1, olass 3 Shock 40 g abock spactrum, in line with MLPRF-2800F, section 4.5.5.4, 1 Electromagnetic compatibility (EMC) in line with MLPRF-2800F, section 4.5.5.4, 1 RF emissions	Temperature range	operating temperature range	0°C to +50°C		
class 3class 3 <thclass 3<="" th="">class 3class 3<th< td=""><td></td><td>storage temperature range</td><td>-40°C to +70°C</td></th<></thclass>		storage temperature range	-40°C to +70°C		
Limital censitatione adamp Preat in time with IEC 600082-30 Attitude up to 3000 m above sea level up to 3000 m above sea level Nonoperating up to 4000 m above sea level up to 4000 m above sea level Mechanical resistance 5 Hz to 150 Hz, max. 1.8 g at 55 Hz; 0.6 g form 55 Hz to 150 Hz, max. 1.8 g at 55 Hz; Vibration sinusoidal 5 Hz to 150 Hz, max. 1.8 g at 55 Hz; Vibration sinusoidal 5 Hz to 150 Hz, max. 1.8 g at 55 Hz; Vibration sinusoidal 5 Hz to 150 Hz, max. 1.8 g at 55 Hz; Vibration sinusoidal 5 Hz to 500 Hz, acceleration 1.2 g (FMS); in line with MILPRF 28800F, section 4.5.5.3.1, class 3 5 Hz to 500 Hz, acceleration 2.08 g (FMS); Shock ad g shock spectrum, in line with MILPRF 28800F, section 4.5.5.4.1 in line with MILPRF 28800F, section 4.5.5.4.1 Electromagnetic compatibility (EMC) in line with CFFR 11/ENF5011, group 1, class A if (for a shielded test setup); Instrumently signification 4.5.5.4.1 in line with CFFR 11/ENF5011, group 1, class A Inmunity signification 4.5.5.4.1 in industrial environments Inmunity signification 4.5.5.4.1 in industrial environments					
Operating up to 3000 m above sea level Nonoperating up to 3000 m above sea level Mechanical resistance 5 Vibration sinusoidal 5 Hz to 150 Hz, max. 1.8 g at 55 Hz; 0.5 g from 55 Hz to 150 Hz, in line with NLOBOB 2-6 Vibration 10 Hz to 50 Hz, in line with MLL-PRF 28800F, section 4.5.5.3 c, class 3 File andom 8 Hz to 500 Hz, acceleration 1.2 g (RMS), in line with NLOBOB 2-6 File andom 8 Hz to 500 Hz, acceleration 1.2 g (RMS), in line with MLL-PRF-28800F, section 4.5.5.3, class 3 Shock 9 d shock spectrum, in line with ML-SPF1-2800F, section 4.5.5.3, class 3 Shock 9 g functional shock, half sine, duration 11 ms, in line with ML-PRF-28800F, section 4.5.5.1, class 3 Shock 9 g functional shock, half sine, duration 11 ms, in with ML-PRF-28800F, section 4.5.5.1, class 3 BF emissions Sine Gamma 9 g functional shock, half sine, duration 11 ms, in line with ICSPR 11/ENS5011, group 1, class A (for a shield at testing); RF emissions Sine Gamma 10 Hz to 50 Hz, institute emitter in line with ICSPR 11/ENS5011, group 1, class A (for a shield at testing); Refinition interval 9 d to 40 Hz to 50, group 1, class A (for a shield at the set pup); Certifications VE VE Certification inte	Climatic resistance	damp heat			
Nonoperating up to 4600 m above sea level Mechanical resistance 5 Hz to 150 Hz, max. 1.8 g at 55 Hz; Vibration Sinusoidal 0.5 g from 55 Hz to 150 Hz, max. 1.8 g at 55 Hz; Vibration Sinusoidal 0.5 g from 55 Hz to 150 Hz, max. 1.8 g at 55 Hz; Vibration Sinusoidal 0.5 g from 55 Hz to 150 Hz, max. 1.8 g at 55 Hz; Vibration Sinusoidal 0.5 g from 55 Hz to 150 Hz, max. 1.8 g at 55 Hz; Vibration Sinusoidal Sinusoidal Sinusoidal Nonce Sinusoidal Sinusoidal Sinusoidal Sinusoidal Sinusoidal Sinusoidal Sinusoidal Sinusoida Ref andom Sinusoidal Sinusoidal Ref emissions Sinusoidal Sinusoidal Sinusoidal Immunity Sinusoidal Sinusoidal Sinusoidal Catifications VDE, CSA, w VDE, CSA, w Catification Catifications VDE, CSA, w VDE, CSA, w Sinusoidal environments Sofer In line with ICISPR 11/EN55011, group 1, class A for a sinueled text setup; instrument complex with sinueled for use in industrial environments Sinueled text setup; instrument complex with sinueled for use in industrial environments Immunity Sinue sinueled in Industrial environments In line with ICISPR 11/EN55201, group 1, class A for a sinueled for use in	Altitude				
Mechanical resistance Section 1000000000000000000000000000000000000	Operating		up to 3000 m above sea level		
Vibration sinusoidal 5 Hz to 150 Hz, max. 1.8 g at 55 Hz; D.5 g from 55 Hz to 150 Hz, in line with NMLPRF-28800F, section 4.5.5.32, class 3 Vibration rendom 8 Hz to 55 Hz, in line with NMLPRF-28800F, section 4.5.5.32, class 3 Shock 8 Hz to 500 Hz, acceleration 1.2 g (RMS), in line with NMLPRF-28800F, section 4.5.5.3.1, class 3 Shock 40 g shock spectrum, in line with MIL-STD-810G, method no. 516.6, procedure I 30 g functional shock, haff sine, duration 1.1 ms, in line with MIL-PRF-28800F, section 4.5.5.4.1 Electromagnetic compatibility (EMC) in line with CISPR 11/ENS5011, group 1, class A for a shelded test satup); instrument comples with emission requirements steplated by ENS5011, ENG1326-1 and ENG1326-2 1 class A, making it suitable for use in industrial environments. RF emissions VDE, CSA ₂₀ , KC Calibration interval 100 V to 240 V ±10% at 50 Hz to 60 Hz and 400 Hz ±5%, max. 2.3 Ato 1.3.A, in line with MIL-PRF-28800F, section 3.5 Power soupply 100 V to 240 V ±10% at 50 Hz to 60 Hz and 400 Hz ±5%, max. 2.3 Ato 1.3.A, in line with MIL-PRF-28800F, section 3.5 Power consumption max. 2.3 Ato 1.3.A, in line with MIL-PRF-28800F, section 3.5 Power consumption max. 2.10 W Safety 100 V to 240 V ±10% at 50 Hz to 60 Hz and 400 Hz ±5%, max. 2.3 Ato 1.3.A, in line with MIL-PRF-28800F, section 3.5 Power consumption max. 210 W Safety <td>Nonoperating</td> <td></td> <td>up to 4600 m above sea level</td>	Nonoperating		up to 4600 m above sea level		
Vibration sinusoidal 0.5 g f com 55 Hz to 150 Hz, in line with EK 00088-2-6 10 Hz to 55 Hz, in line with MIL-PFF-28800F, section 4.5.5.32, class 3 8 Hz to 500 Hz, acceleration 1.2 g (RMS), in line with EK 00088-2-64 5 Hot 500 Hz, acceleration 2.058 g (RMS), in line with EK 00088-2-64 8 Hz to 500 Hz, acceleration 2.058 g (RMS), in line with MIL-PFF-28800F, section 4.5.5.3.1, class 3 5 Shock 40 g shock spectrum, in line with MIL-STD-810G, method no. 516.6, procedure I 7 Hot 500 Hz, acceleration 2.058 g (RMS), in line with MIL-PFF-28800F, section 4.5.5.4.1 Electromagnetic compatibility (EMC) 8 Fe emissions Fe emissions Fe emissions Califoration interval Power supply AC supply AC supply Setup Setup Setup Setup Setup Power consumption Setup	Mechanical resistance				
ieradom section 4.55.32, class 3 B Hz to 500 Hz, acceleration 1.2 g (RMS), in line with ENROD68-2-64 SH2 to 500 Hz, acceleration 2.058 g (RMS), in line with MILPRF-28800F, section 4.55.3.1, class 3 Shock 40 g shock spectrum, in line with MILPRF-28800F, section 4.55.3.1, class 3 Shock 90 g functional shock, half sine, duration 11 ms, in line with MILPRF-28800F, section 4.55.4.1 Electromagnetic compatibility (EMC) in line with MILPRF-28800F, section 4.55.4.1 Fe emissions shield test steph); instrument comples with emission requirements stipulated by ENSD11, group 1, class A (for a shield et steph); instrument comples with emission requirements in industrial environments Immunity environments Calibration interval 90 s for equipment used in industrial environments ¹⁸ Calibration interval in line with ECCFN04326-1 and ENG1326-1 class A, making it suitable for use in industrial environments AC supply VDE, cSA _{hub} KC Calibration interval in out stip of the 2, immunity test requirements for equipment used in industrial environments ¹⁸ Power consumption max 2.3 A to 1.3 A, in line with MIL-PRF-28800F, section 3.5 Power consumption max 2.10 W Safety in line with MIL-PRF-28800F, section 3.5 Power consumption max 2.10 W Safety in line with MIL-PRF-28800F	Vibration	sinusoidal	0.5 g from 55 Hz to 150 Hz,		
in line with EN 60068-2-64 in line with EN 60068-2-64 in line with EN EN 60068-2-64 in line with MLPF 28800F, section 4.5.5.3.1, class 3 Shock 40 g shock spectrum, in line with MLESTD-810G, method no. 516.6, procedure 1 30 g functional shock, half sine, duration 11 ms, in line with ML-PRF-28800F, section 4.5.5.4.1 Electromagnetic compatibility (EMC) In line with CISPR 11/ENF55011, group 1, class A (for a shielded test setup); instrument complies with emission requirements stipulated by EN55011, EN 61326-2-1 and EN 61326-2-1 class A, making it suitable for use in industrial environments Immunity in line with IEC/EN(61326-1 table 2, immunity test requirements for equipment used in industrial environments [®] Certifications VDE, cSA _{us} KC Calibration interval 100 V to 240 V ±10% at 504, making it suitable for use an in industrial environments [®] Power supply Section 3.5 AC supply 100 V to 240 V ±10% at 504, making it suitable for use an in industrial environments [®] Power consumption max. 210 W Section section 3.5, in line with MIL-PRF-28800F, section 3.5, in line with					
in line with MLL-PRF-28900F, section 4.5.5.3.1, class 3Shock40 g shock spectrum, in line with MLL-STD-810G, method no. 516.6, procedure 1 30 g functional shock, half sine, duration 11 ms, in line with MLL-PRF-2800F, section 4.5.5.4.1Electromagnetic compatibility (EMC)in line with MLL-PRF-2800F, section 4.5.5.4.1Electromagnetic compatibility (EMC)in line with MLL-PRF-2800F, section 4.5.5.4.1Electromagnetic compatibility (EMC)in line with MLL-PRF-2800F, section 4.5.5.4.1RF emissionsin line with MLL-PRF-2800F, section 4.5.5.4.1Immunityin shift det est setup): instrument complies with emission requirements stipulated by ENS5011, EN61326-1 and EN61326-1 class A, making it suitable for use in industrial environmentsImmunitycertificationsCertificationsVDE, CSA _{US} , KCCalibration interval1 yearPower supplyin line with MLL-PRF-2800F, section 3.5Power consumptionmax. 2.3 A to 1.3 A, in line with MIL-PRF-2800F, section 3.5Power consumptionmax. 2.10 WSafetyin line with IEC61010-1, EN61010-1, CANUCSA-C22.2 No.61010-1, UL 61010-1Methanical datawithout options, nominalWeightwithout options, nominalWeightwithout options, nominal		random			
Shock method no. 516.6, procedure 1 30 g functional shock, half sine, duration 11 ms, in line with MIL-PRF-28800F, section 4.5.5.4.1 Electromagnetic compatibility (EMC) RF emissions stipulated by EN55011, group 1, class A (for a shielded test setup); instrument complies with emission requirements stipulated by EN55011, EN61326-1 and EN61326-2-1 class A, making it suitable for use in industrial environments Immunity in line with IEC/EN61326-1 table 2, immunity test requirements for equipment used in industrial environments Catibration interval VDE, _cCSA _{LSF} KC Catibration interval 100 V to 240 V ± 10% at 50 Hz to 60 Hz and 400 Hz ± 5%, max. 2.3 A to 1.3 A, in line with MIL-PRF-28800F, section 3.5 Power consumption max. 210 W Safety in line with IEC61010-1, EN61010-1, CAN/CSA-C22.2 No. 61010-1, UL 61010-1 Mechanical data 144 mm x 279 mm x 162 mm Dimensions W x H x D 414 mm x 279 mm x 162 mm Weight without options, nominal 6.0 kg (13.23 lb)			in line with MIL-PRF-28800F, section 4.5.5.3.1,		
Electromagnetic compatibility (EMC) RF emissions in line with CISPR 11/ENS5011, group 1, class A (for a shielded test setup); instrument complies with emission requirements stipulated by ENS5011, EN61326-1 and EN61326-2-1 class A, making it suitable for use in industrial environments Immunity environments Certifications VDE, cCSA _{ver} KC Calibration interval 1 year Power supply stolated to the stolated to t	Shock		40 g shock spectrum, in line with MIL-STD-810G, method no. 516.6, procedure I		
RF emissionsin line with CISPR 11/EN55011, group 1, class A (for a shielded test setup); instrument complies with emission requirements stipulated by EN55011, EN61326-1 and EN61326-2-1 class A, making it suitable for use in industrial environmentsImmunityImmunityin line with IEC/EN61326-1 table 2, immunity test requirements for equipment used in industrial environmentsCertificationsVDE, cCSA _{us} , KCCalibration interval1 yearPower supply100 V to 240 V ±10% at 50 Hz to 60 Hz and 400 Hz ±5%, max. 2.3 A to 1.3 A, in line with MIL-PRF-28800F, section 3.5Power consumptionmax. 2.10 WSafetyIn line with IEC61010-1, EN61010-1, CAN/CSA-C22.2 No. 61010-1, UL 61010-1Mechanical dataW × H × DWightwithout options, nominal6.0 kg (13.23 lb)			.		
RF emissions(for a shielded test setup); instrument complies with emission requirements stipulated by EN55011, EN61326-1 and EN61326-21 class A, making it suitable for use in industrial environmentsImmunityImmunityin line with IEC/EN61326-1 table 2, immunity test requirements for equipment used in industrial environments®CertificationsVDE, cCSA _{US} , KCCalibration interval1 yearPower supplyImage: State 1 and State 1 and State 2 and A and State 1 and State 2 and A and State 2 and A and	Electromagnetic compatibility (EMC)				
Immunityrequirements for equipment used in industrial environments®CertificationsVDE, cCSAUSY KCCalibration interval1 yearPower supply100 V to 240 V ±10% at 50 Hz to 60 Hz and 400 Hz ±5%, max. 2.3 A to 1.3 A, in line with MIL-PRF-28800F, section 3.5Power consumptionmax. 2.10 WSafetyin line with IEC 61010-1, EN 61010-1, CAN/CSA-C22.2 No. 61010-1, UL 61010-1Mechanical datawithout options, nominalWeightwithout options, nominal	RF emissions		(for a shielded test setup); instrument complies with emission requirements stipulated by EN55011, EN61326-1 and EN61326-2-1 class A, making it suitable for use		
Calibration interval 1 year Power supply 100 V to 240 V ±10% at 50 Hz to 60 Hz and 400 Hz ±5%, max. 2.3 A to 1.3 A, in line with MIL-PRF-28800F, section 3.5 Power consumption max. 2.10 W Safety max. 210 W Dimensions W × H × D 414 mm × 279 mm × 162 mm (16.3 in × 10.99 in × 6.38 in) Weight without options, nominal 6.0 kg (13.23 lb)	Immunity				
Power supply Intersection Intersection<	Certifications		VDE, _c CSA _{us} , KC		
AC supply100 V to 240 V $\pm 10\%$ at 50 Hz to 60 Hz and 400 Hz $\pm 5\%$, max. 2.3 A to 1.3 A, in line with MIL-PRF-28800F, section 3.5Power consumptionmax. 210 WSafetyin line with IEC 61010-1, EN 61010-1, CAN/CSA-C22.2 No. 61010-1, UL 61010-1Mechanical dataDimensionsW × H × DWeightwithout options, nominal6.0 kg (13.23 lb)	Calibration interval		1 year		
AC supply50 Hz to 60 Hz and 400 Hz ±5%, max. 2.3 A to 1.3 A, in line with MIL-PRF-28800F, section 3.5Power consumptionmax. 210 WSafetyin line with IEC 61010-1, EN 61010-1, CAN/CSA-C22.2 No. 61010-1, UL 61010-1Mechanical datawith v PMDimensionsW × H × DWeightwithout options, nominal6.0 kg (13.23 lb)	Power supply				
Safety in line with IEC 61010-1, EN 61010-1, CAN/CSA-C22.2 No. 61010-1, UL 61010-1 Mechanical data #14 mm × 279 mm × 162 mm (16.3 in × 10.99 in × 6.38 in) Weight without options, nominal 6.0 kg (13.23 lb)	AC supply		50 Hz to 60 Hz and 400 Hz $\pm 5\%$, max. 2.3 A to 1.3 A, in line with MIL-PRF-28800F,		
Safety CAN/CSA-C22.2 No. 61010-1, UL 61010-1 Mechanical data V H × D 414 mm × 279 mm × 162 mm (16.3 in × 10.99 in × 6.38 in) Weight without options, nominal 6.0 kg (13.23 lb)	Power consumption		max. 210 W		
Dimensions W × H × D 414 mm × 279 mm × 162 mm (16.3 in × 10.99 in × 6.38 in) Weight without options, nominal 6.0 kg (13.23 lb)	Safety				
Dimensions W × H × D (16.3 in × 10.99 in × 6.38 in) Weight without options, nominal 6.0 kg (13.23 lb)	Mechanical data				
	Dimensions	W × H × D			
Rackmount height with R&S°ZZA-MXO4 rackmount kit 6 HU	Weight	without options, nominal	6.0 kg (13.23 lb)		
	Rackmount height	with R&S®ZZA-MXO4 rackmount kit	6 HU		

 $^{\scriptscriptstyle (8)}$ Test criterion is displayed noise level within ±1 div for an input sensitivity of 5 mV/div.

ORDERING INFORMATION

Designation	Туре	Order No.
MXO 4 series, base unit		
Oscilloscope, 200 MHz, 4 channels	MXO 4	1335.5050.04
Base unit (including standard accessories: 700 MHz passive probe (10:1) per channel, accessories bag, quic	k start guide, power co	ord)
Choose your bandwidth upgrade		
Upgrade of MXO 4 to 350 MHz bandwidth	R&S®MXO4-B243	1335.4276.02
Upgrade of MXO 4 to 500 MHz bandwidth	R&S®MXO4-B245	1335.4299.02
Upgrade of MXO 4 to 1 GHz bandwidth	R&S®MXO4-B2410	1335.4318.02
Upgrade of MXO 4 to 1.5 GHz bandwidth	R&S®MXO4-B2415	1335.4330.02
Choose your options		
Mixed signal option, for MXO 4 series with 16 digital channels	R&S®MXO4-B1	1335.4130.02
Arbitrary waveform generator, 100 MHz, 2 analog channels	R&S®MXO4-B6	1335.4147.02
Memory upgrade to 800 Mpoints on 2 channels	R&S®MXO4-B108	1335.5772.02
Power analysis	R&S®MXO4-K31	1335.5566.02
Frequency response analysis	R&S®MXO4-K36	1335.5572.02
Bus analysis	R&S®MXO4-K500	1335.5243.02
Low speed serial buses (I ² C/SPI/QuadSPI/UART/RS-232/RS-422/RS-485)	R&S [®] MXO4-K510	1335.5195.02
Automotive protocols (CAN/CAN FD/CAN XL/LIN/SENT)	R&S®MXO4-K520	1335.5550.02
Aerospace protocols (ARINC 429, MIL-STD-1553)	R&S®MXO4-K530	1335.5208.02
MIPI low speed protocols (SPMI/REFE/I ³ C)	R&S®MXO4-K550	1335.5214.02
Automotive Ethernet protocols (10BASE-T1S)	R&S®MXO4-K560	1335.5943.02
Application bundle with the following options: R&S®MXO4-B6, R&S®MXO4-K31, R&S®MXO4-K36, R&S®MXO4-K510, R&S®MXO4-K520	R&S®MXO4-PK1	1335.5237.02
R&S [®] ScopeStudio Software	R&S [®] MXO-PC	1801.9005.02
R&S°ScopeStudio protocol decode option	R&S [®] MXO-PC-K1	1804.8874.02
Choose your additional probes		
Passive probes: single-ended		
700 MHz, 10 MΩ, 10:1, 400 V, 9.5 pF, 2.5 mm	R&S®RT-ZP11	1803.0005.02
500 MHz, 10 MΩ, 10:1, 400 V, 9.5 pF, 2.5 mm	R&S®RT-ZP10	1409.7550.00
500 MHz, 10 MΩ, 10:1, 300 V, 10 pF, 5 mm	R&S®RT-ZP05S	1333.2401.02
38 MHz, 1 MΩ, 1:1, 55 V, 39 pF, 2.5 mm	R&S®RT-ZP1X	1333.1370.02
Active broadband probes: single-ended		
1.0 GHz, 1 MΩ, Rohde&Schwarz probe interface	R&S®RT-ZS10E	1418.7007.02
1.0 GHz, 1 MΩ, R&S [®] ProbeMeter, micro button, Rohde&Schwarz probe interface	R&S®RT-ZS10	1410.4080.02
1.5 GHz, 1 M Ω , R&S [®] ProbeMeter, micro button, Rohde&Schwarz probe interface	R&S®RT-ZS20	1410.3502.02
Active broadband probes: differential		
1.0 GHz, 1 MΩ, R&S®ProbeMeter, micro button, including 10:1 external attenuator, 1 MΩ, 60 V DC, 42.4 V AC (peak), Rohde&Schwarz probe interface	R&S®RT-ZD10	1410.4715.02
1.5 GHz, 1 MΩ, R&S [®] ProbeMeter, micro button, Rohde&Schwarz probe interface	R&S®RT-ZD20	1410.4409.02
Power rail probe		
2.0 GHz, 1:1, 50 k Ω , ±0.85 V, ±60 V offset, Rohde&Schwarz probe interface	R&S®RT-ZPR20	1800.5006.02
High voltage probes: passive		
250 MHz, 100:1, 100 MΩ, 850 V, 6.5 pF	R&S®RT-ZH03	1333.0873.02
400 MHz, 100:1, 50 MΩ, 1000 V, 7.5 pF	R&S®RT-ZH10	1409.7720.02
400 MHz, 1000:1, 50 MΩ, 1000 V, 7.5 pF 400 MHz, 1000:1, 50 MΩ, 1000 V, 7.5 pF	R&S®RT-ZH11	1409.7720.02
High voltage probes: differential		1403.7737.02
200 MHz, 250:1/25:1, 5 MΩ, 750 V (peak), 300 V (RMS) CAT III, Rohde&Schwarz probe interface	R&S®RT-ZHD07	1800.2307.02
100 MHz, 500:1/50:1, 10 MΩ, 1500 V (peak), 1000 V (RMS) CAT III, Rohde&Schwarz probe interface	R&S®RT-ZHD15	1800.2107.02
200 MHz, 500:1/50:1, 10 MΩ, 1500 V (peak), 1000 V (RMS) CAT III, Rohde&Schwarz probe interface	R&S®RT-ZHD16	1800.2207.02
100 MHz, 1000:1/100:1, 40 MΩ, 6000 V (peak), 1000 V (RMS) CAT III, Rohde&Schwarz probe interface	R&S®RT-ZHD60	1800.2007.02

Designation	Туре	Order No.		
Current probes				
20 kHz, AC/DC, 0.01 V/A and 0.001 V/A, ±200 A and ±2000 A, BNC interface	R&S®RT-ZC02	1333.0850.02		
100 kHz, AC/DC, 0.1 V/A, 30 A, BNC interface	R&S®RT-ZC03	1333.0844.02		
2 MHz, AC/DC, 0.01 V/A, 500 A (RMS), Rohde&Schwarz probe interface	R&S®RT-ZC05B	1409.8204.02		
10 MHz, AC/DC, 0.01 V/A, 150 A (RMS), BNC interface	R&S®RT-ZC10	1409.7750K02		
10 MHz, AC/DC, 0.01 V/A, 150 A (RMS), Rohde&Schwarz probe interface	R&S®RT-ZC10B	1409.8210.02		
50 MHz, AC/DC, 0.1 V/A, 30 A (RMS), Rohde&Schwarz probe interface	R&S®RT-ZC15B	1409.8227.02		
100 MHz, AC/DC, 0.1 V/A, 30 A (RMS), BNC interface	R&S®RT-ZC20	1409.7766K02		
100 MHz, AC/DC, 0.1 V/A, 30 A (RMS), Rohde&Schwarz probe interface	R&S®RT-ZC20B	1409.8233.02		
120 MHz, AC/DC, 1 V/A, 5 A (RMS), BNC interface	R&S®RT-ZC30	1409.7772K02		
EMC near-field probe set				
Compact probe set for E and H near-field measurements, 30 MHz to 3 GHz	R&S®HZ-15	1147.2736.02		
Logic probe ¹⁾				
400 MHz logic probe, 8 channels	R&S®RT-ZL04	1333.0721.02		
Probe accessories				
Accessory set, for R&S®RT-ZP11 passive probe (2.5 mm probe tip)	R&S®RT-ZA1	1409.7566.00		
Power supply, for R&S®RT-ZC10/-ZC20/-ZC30 current probes	R&S®RT-ZA13	1409.7789.02		
External attenuator 10:1, 2.0 GHz, 1.3 pF, 60 V DC, 42.4 V AC (peak), for R&S®RT-ZD20/-ZD30 probes	R&S®RT-ZA15	1410.4744.02		
Probe pouch, for logic probes	R&S®RT-ZA19	1335.7875.02		
Power deskew and calibration test fixture	R&S®RT-ZF20	1800.0004.02		
3D positioner with central tensioning knob for easy clamping and positioning of probes (span width: 200 mm, clamping range: 15 mm)	R&S®RT-ZAP	1326.3641.02		
Choose your accessories				
Front cover	R&S®MXO4-Z1	1335.4360.02		
Soft case	R&S®MXO4-Z3	1335.5589.02		
Transit case	R&S®MXO4-Z4	1335.5595.02		
19" rackmount kit, 6 HU	R&S®ZZA-MXO4	1335.5108.02		
VESA mounting interface	100 mm × 100 mm pattern	n VESA standard		

Warranty		
Base unit		3 years
All other items ²⁾		1 year
Service options		
Extended warranty, one year	R&S®WE1	
Extended warranty, two years	R&S®WE2	
Extended warranty with calibration coverage, one year	R&S®CW1	Contact your local Rohde&Schwarz
Extended warranty with calibration coverage, two years	R&S®CW2	sales office.
Extended warranty with accredited calibration coverage, one year	R&S®AW1	
Extended warranty with accredited calibration coverage, two years	R&S®AW2	

The R&S®MXO4-B1 mixed signal option contains two R&S®RT-ZL04 logic probes.
 For options installed, the remaining base unit warranty applies if longer than 1 year. Exception: all batteries have a 1 year warranty.

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- ► Solution finding/purchase
- Technical startup/application development/integration
- ► Training
- ► Operation/calibration/repair



OSCILLOSCOPE PORTFOLIO

	R&S®RTH1000	R&S®RTC1000	R&S®RTB 2	R&S®RTM3000
Vertical system				
Bandwidth ¹⁾	60/100/200/350/500 MHz	50/70/100/200/300 MHz	70/100/200/300 MHz	100/200/350/500 MHz/1 GHz
Number of channels	2 plus DMM/4	2	2/4	2/4
Vertical resolution; system architecture	10 bit; 16 bit	8 bit; 16 bit	10 bit; 16 bit	10 bit; 16 bit
V/div, 1 MΩ	2 mV to 100 V	1 mV to 10 V	1 mV to 5 V	500 µV to 10 V
V/div, 50 Ω	-			500 μV to 1 V
Digital channels	8	8	16	16
Horizontal system				
Sampling rate per channel (in Gsample/s)	1.25 (4-channel model); 2.5 (2-channel model); 5 (all channels interleaved)	1; 2 (2 channels interleaved)	1.25; 2.5 (2 channels interleaved)	2.5; 5 (2 channels interleaved)
Maximum memory (per channel; 1 channel active)	125 kpoints (4-channel model); 250 kpoints (2-channel model); 500 kpoints	1 Mpoint; 2 Mpoints	10 Mpoints; 20 Mpoints	40 Mpoints; 80 Mpoints
Segmented memory	standard, 50 Mpoints	-	standard, 160 Mpoints	option, 400 Mpoints
Acquisition rate (in waveforms/s)	50 000	10 000	50 000 (300 000 in fast seg- mented memory mode)	64000 (2000000 in fast segmented memory mode ²⁾)
Trigger				
Types	digital	analog	analog	analog
Sensitivity	-	-	at 1 mV/div: > 2 div	at 1 mV/div: > 2 div
Analysis				
Mask test	tolerance mask	tolerance mask	tolerance mask	tolerance mask
Mathematics	elementary	elementary	basic (math on math)	basic (math on math)
Serial protocols triggering and decoding ¹⁾	I²C, SPI, UART/RS-232/RS-422/ RS-485, CAN, LIN, CAN FD, SENT	I²C, SPI, UART/RS-232/RS-422/ RS-485, CAN, LIN	I²C, SPI, UART/RS-232/RS-422/ RS-485, CAN, LIN	I²C, SPI, UART/RS-232/RS-422/RS-485, CAN, LIN, I²S, MIL-STD-1553, ARINC429
Applications ^{1), 2)}	high-resolution frequency counter, advanced spectrum analysis, harmonics analysis, user scripting	digital voltmeter (DVM), com- ponent tester, fast Fourier trans- form (FFT)	digital voltmeter (DVM), fast Fourier transform (FFT), frequency response analysis	power, digital voltmeter (DVM), spectrum analysis and spectrogram, frequency response analysis
Compliance testing ^{1), 2)}	-	-	-	-
Display and operation		0.51		
Size and resolution	7" touchscreen, 800 × 480 pixel	6.5", 640 × 480 pixel	10.1" touchscreen, 1280 × 800 pixel	10.1" touchscreen, 1280 × 800 pixel
General data				
Dimensions in mm (W \times H \times D)	201 × 293 × 74	285 × 175 × 140	390 × 220 × 152	390 × 220 × 152
Weight in kg	2.4	1.7	2.5	3.3
Battery	lithium-ion, > 4 h	-	-	-

¹⁾ Upgradeable. ²⁾ Requires an option.









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MXO 4	MXO 5/MXO 5C	R&S®RT06	R&S®RTP
200/350/500 MHz/1/1.5 GHz	100/200/350/500 MHz/1/2 GHz	600 MHz/1/2/3/4/6 GHz	4/6/8/13/16 GHz
4	4/8	4	4
12 bit; 18 bit	12 bit; 18 bit	8 bit; 16 bit	8 bit; 16 bit
500 1/1 401/	500 144 4014		with R&S®RT-Z1M:
500 µV to 10 V	500 μV to 10 V	1 mV to 10 V (HD mode: 500 µV to 10 V)	2 mV to 10 V (HD mode: 1 mV to 10 V)
500 µV to 1 V	500 µV to 1 V	1 mV to 1 V (HD mode: 500 μV to 1 V)	2 mV to 1 V (HD mode: 1 mV to 1 V)
16	16	16	16
2.5; 5 (2 channels interleaved)	5 on 4 channels; 2.5 on 8 channels (2 channels interleaved)	10; 20 (2 channels interleaved in 4 GHz and 6 GHz model)	20; 40 (2 channels interleaved)
standard: 400 Mpoints; max. upgrade: 800 Mpoints ²⁾	standard: 500 Mpoints max. upgrade: 1 Gpoint ²⁾	standard: 200 Mpoints/800 Mpoints; max. upgrade: 1 Gpoint/2 Gpoints	standard: 100 Mpoints/400 Mpoints; max. upgrade: 3 Gpoints
standard: 10 000 segments; option: 1 000 000 segments	standard: 10 000 segments; option: 1 000 000 segments	standard	standard
> 4 500 000	> 4500000 on 4 channels	1 000 000 (2 500 000 in ultra-segmented memory mode)	750 000 (> 3 000 000 in ultra-segmented memory mode)
advanced (includes zone trigger), digital trigger (15 trigger types)	advanced (includes zone trigger), digital trigger (15 trigger types)	advanced (includes zone trigger), digital trigger (15 trigger types), high speed serial pattern trigger including 5 Gbps clock data recovery (CDR) ²⁾	advanced (includes zone trigger), digital trigger (14 trigger types) with real-time deembedding ²), high speed serial pattern trigger including 8/16 Gbps clock data recovery (CDR) ²)
0.0001 div, across full bandwidth, user controllable	0.0001 div, across full bandwidth, user controllable	0.0001 div, across full bandwidth, user controllable	0.0001 div, across full bandwidth, user controllable
user configurable, hardware based	user configurable, hardware based	user configurable, hardware based	user configurable, hardware based
advanced (formula editor)	advanced (formula editor)	advanced (formula editor, Python interface)	advanced (formula editor, Python interface)
I ² C, SPI, UART/RS-232/RS-422/ RS-485, CAN, CAN FD, CAN XL, LIN, ARINC429, MIL-STD-1553, SPMI, 10BASE-T1S, QUAD-SPI, SENT, RFFE, I ³ C	I ² C, SPI, UART/RS-232/RS-422/ RS-485, CAN, CAN FD, CAN XL, LIN, ARINC429, MIL-STD-1553, SPMI, 10BASE-T1S, 100BASE-T1, QUAD-SPI, SENT, RFFE, I ³ C	I ² C, SPI, UART/RS-232/RS-422/RS-485, CAN, LIN, I ² S, MIL-STD-1553, ARINC 429, FlexRay, CAN FD, MIPI RFFE, USB 2.0/HSIC, MDIO, 8b10b, Ethernet, Manchester, NRZ, SENT, MIPI D-PHY, SpaceWire, MIPI M-PHY/UniPro, CXPI, USB 3.1 Gen 1, USB- SSIC, PCIe 1.1/2.0, USB Power Delivery, Automotive Ethernet 100/1000BASE-T1	I ² C, SPI, UART/RS-232/RS-422/RS-485, SENT, CAN, LIN, CAN FD, MIL-STD-1553, ARINC 429, SpaceWire, USB 2.0/HSIC/PD, USB 3.1 Gen 1/ Gen 2/SSIC, PCIe 1.1/2.0/3.0, 8b10b, MIPI RFFE, MIPI D/M-PHY/UniPro, Automotive Ethernet 100/1000BASE-T1, Ethernet 10/100BASE-TX, MDIO, Manchester, NRZ
power, digital voltmeter (DVM), frequency response analysis	power, digital voltmeter (DVM), frequency response analysis	power, advanced spectrum analysis and spectrogram, jitter and noise decomposition, clock data recovery (CDR), I/Q data and RF analysis (R&S®VSE), deembedding, embedding, equalization, PAM-N, TDR/TDT analysis, advanced eye diagram	advanced spectrum analysis and spectrogram, jitter and noise decomposition, real-time deembedding, embedding, equalization, PAM-N, TDR/TDT analy- sis, I/Q data and RF analysis (R&S [®] VSE), advanced eye diagram
-		see specifications (PD 5216.1640.22)	see specifications (PD 3683.5616.22)
13.3" touchscreen, 1920 × 1080 pixel (Full HD)	for MXO 5 only: 15.6" touchscreen, 1920 × 1080 pixel (Full HD)	15.6" touchscreen, 1920 × 1080 pixel (Full HD)	13.3" touchscreen, 1920 × 1080 pixel (Full HD)
414 × 279 × 162	MXO 5: 445 × 314 × 154 MXO 5C: 445 × 105 × 405	450 × 315 × 204	441 × 285 × 316
6	MXO 5: 9 MXO 5C: 8.7	10.7	18
-	-	-	-

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